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OMB Control Number: TKTK-TKTK

Expiration Date: Month/Date/Year

#### DEFENSE INDUSTRIAL BASE ASSESSMENT: THE U.S. INTEGRATED CIRCUIT DESIGN AND MANUFACTURING INDUSTRY



#### **SCOPE OF ASSESSMENT**

The U.S. Department of Commerce, Bureau of Industry and Security (BIS), Office of Technology Evaluation (OTE), is conducting a survey and assessment of the health and competitiveness of the U.S. design and manufacturing infrastructure available for producing Integrated Circuit products required for meeting U.S. national security needs. The goal of this study is to provide decision makers in the U.S. Departments of Defense, Energy, Justice, Homeland Security, and other Executive Branch agencies with detailed information on (1) the health and status of Integrated Circuit design and manufacturing capabilities remaining in the United States; and (2) the outlook for maintaining these activities in the future. The scope of this effort encompasses Integrated Circuit design and manufacturing resources, including the supply chain.

#### RESPONSE TO THIS SURVEY IS REQUIRED BY LAW

A response to this survey is required by law (50 U.S.C. App. Sec. 2155). Failure to respond can result in a maximum fine of \$10,000, imprisonment of up to one year, or both. Information furnished herewith is deemed confidential and will not be published or disclosed except in accordance with Section 705 of the Defense Production Act of 1950, as amended (50 U.S.C App. Sec. 2155). Section 705 prohibits the publication or disclosure of this information unless the President determines that its withholding is contrary to the national defense. Information will not be shared with any non-government entity, other than in aggregate form. The information will be protected pursuant to the appropriate exemptions from disclosure under the Freedom of Information Act (FOIA), should it be the subject of a FOIA request.

Notwithstanding any other provision of law, no person is required to respond to nor shall a person be subject to a penalty for failure to comply with a collection of information subject to the requirements of the Paperwork Reduction Act unless that collection of information displays a currently valid OMB Control Number.

#### **BURDEN ESTIMATE AND REQUEST FOR COMMENT**

Public reporting burden for this collection of information is estimated to average 14 hours per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing the collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information to BIS Information Collection Officer, Room 6883, Bureau of Industry and Security, U.S. Department of Commerce, Washington, D.C. 20230, and to the Office of Management and Budget, Paperwork Reduction Project (OMB Control No. TKTK-TKTK), Washington, D.C. 20503.

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| Section I | : General Instructions  |
|           | Your organization is required to complete this survey of the U.S. Integrated Circuit industry using an Excel template, which can be downloaded from the BIS website: http://bis.doc.gov/chipsurvey  |
| A.        | If you are not able to download the survey document, at your request BIS, staff will e-mail the Excel survey template directly to you.  |
|           | For your convenience, a PDF version of the survey and required drop-down content is available on the BIS website to aid internal data collection. DO NOT SUBMIT the PDF version of the survey as your response to BIS. Should this occur, your organization will be required to resubmit the survey in the requested Excel format.                          |
|           | Respond to every question. Surveys that are not fully completed will be returned for completion. Use the comment boxes to provide any information to supplement responses provided in the survey form. Make sure to record a complete answer in the cell provided, even if the cell does not appear to expand to fit all the information.                   |
| B.        | DO NOT CUT AND PASTE RESPONSES WITHIN THIS SURVEY.  Survey inputs should be completed by typing in responses or by use of a drop-down menu. The use of cut and paste can corrupt the survey template. If your survey response is corrupted as a result of cut and paste responses, a new survey will be sent to your organization for immediate completion. |
| C.        | Do not disclose any classified information in this survey form.   |
| D.        | Estimates are sometimes acceptable where indicated, but in sections that do not explicitly allow estimates you must contact BIS survey support staff before including estimates.  |
| E.        | Upon completion of the survey, final review, and certification, transmit the survey document via e-mail to: <a href="mailto:chipstudy@bis.doc.gov">chipstudy@bis.doc.gov</a>  |
| F.        | Questions related to the survey should be directed to BIS survey support staff at <a href="mailto:chipstudy@bis.doc.gov">chipstudy@bis.doc.gov</a> (E-mail is the preferred method of contact).   |
| 1.        | You may also speak with a member of the BIS survey support staff by calling (202) 482-6339  |
|           | For questions related to the overall scope of this Industrial Base assessment, contact:   |
| G.        | Brad Botwin, Director, Industrial Studies Office of Technology Evaluation, Room 1093 U.S. Department of Commerce 1401 Constitution Avenue, NW Washington, DC 20230  |
|           | DO NOT submit completed surveys to Mr. Botwin's postal or e-mail address; all surveys must be submitted electronically to XXX   |
|           | BUSINESS CONFIDENTIAL - Per Section 705(d) of the Defense Production Act  |
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| Section II: Definitions  |   |      |
| Term   | Definition  |      |
| Applied Research   | Systematic study to gain knowledge or understanding necessary to determine the means by which a recognized and specific need may be met. This activity includes work leading to the production of useful materials, devices, and systems or methods, including design, development, and improvement of prototypes and new processes.  |      |
| Authorizing Official   | Executive officer of the organization or business unit or other individual who has the authority to execute this survey on behalf of the organization.  |      |
| Basic Research   | Systematic, scientific study directed toward greater knowledge or understanding of the fundamental aspects of phenomena and of observable facts.  |      |
| Capability   | The ability to perform defined design and/or manufacturing steps for producing integrated circuit products within organization's own facilities and with its own employees with little or no outsourcing.   | an   |
| Capital Expenditures   | Investments made by an organization in buildings, equipment, property, and systems where the expense is depreciated. This does not include expenditures for consumable materials, other operating expenses and salari associated with normal business operations.   | ies  |
| Commercial and Government Entity<br>(CAGE) Code                  | Commercial and Government Entity (CAGE) Code identifies companies doing or seeking to do business with the U.S. Federal Government. The code is used to support mechanized government systems and provides a standardized method of identifying a given facility at a specific location. Find CAGE codes at <a href="https://cage.dla.mil/search/">https://cage.dla.mil/search/</a> .   | Э    |
| Commercially Sensitive Information (CSI)                         | Privileged or proprietary information which, if compromised through alteration, corruption, loss, misuse, or unauthorized disclosure, could cause serious harm to the information's owners.   |      |
| Customer   | An entity to which an organization directly delivers the product or service that the facility produces. A customer n be another organization or another facility owned by the same parent organization. The customer may be the er user for the item but often will be an intermediate link in the supply chain, adding additional value before transferring the item to yet another customer.  |      |
| Cyber Security   | The body of technologies, processes, and practices designed to protect networks, computers, programs, and da from attack, damage, or unauthorized access.   | ıta  |
| Data Universal Numbering System (DUNS)                           | A nine-digit numbering system that uniquely identifies an individual business. Find DUNS numbers at <a href="http://fedgov.dnb.com/webform">http://fedgov.dnb.com/webform</a> .   |      |
| Development  | The design, development, simulation, or experimental testing of prototype or experimental hardware or systems, validate technological feasibility or concept of operation, to reduce technological risk, or to provide test systems prior to production approval.   | , to |
| Design   | Design activity required to implement a product concept in support of the manufacture of the Integrated Circuit product at a fabrication facility.  |      |
| Facility   | A facility can constitute a single building or multiple buildings functioning as a unified design, fabrication, or packaging facility. Design, fabrication, and packing, test and assembly operations must be identified separately. Individual wafer fabrication facilities serving distinct sets of technology nodes should be identified separately everoperating on a single campus.  |      |
| Full Time Equivalent (FTE)<br>Employees                          | Employees who work for 40 hours in a normal work week. Convert part-time employees into "full time equivalent by taking their work hours as a fraction of 40 hours.   | nts" |
| Harmonized Tariff Schedule (HTS)                                 | The Harmonized Tariff Schedule (HTS) is the statute used to determine tariff classifications for goods imported in the United States and maintained and published by the United States International Trade Commission. The HTS based on the International Harmonized System.  |      |
| Integrated Circuit   | Analog or digital devices that incorporate transistors, diodes, capacitors, resistors, and other circuit elements that are integrated on a single substrate (chip), typically silicon.  | at   |
| Location   | For the purpose of this survey, a location is a single contiguous site.   |      |
| Manufacturing  | The production of a working Integrated Circuit product in a fabrication facility.   |      |
| Neutron Hardened   | Integrated Circuit products incorporating design features and/or physical characteristics that can withstand the damaging effects of high-speed neutrons, gamma rays, and electromagnetic pulses that accompany a nuclear weapons detonation. Most CMOS[1] technologies are inherently neutron hardened without any specific effort on the part of an ICs designer/manufacturer. For "minority carrier" IC devices that are affected by neutron-induced displacement damage, a level of 1X1014 n/cm2 (1MeV equivalent fluence) is the accepted standard.[2] | I    |
| North American Industry<br>Classification System (NAICS)<br>Code | North American Industry Classification System (NAICS) codes identify the category of product(s) or service(s) provided by an organization. Find NAICS codes at <a href="http://www.census.gov/epcd/www/naics.html">http://www.census.gov/epcd/www/naics.html</a>  |      |
| Organization   | A company, firm, laboratory, or other entity that owns or controls one or more U.S. establishment capable of designing and/or manufacturing Integrated Circuit products. A company may be an individual proprietorship, partnership, joint venture, or corporation (including any subsidiary corporation in which more than 50 percent of outstanding voting stock is owned by a business trust, cooperative, trustee(s) in bankruptcy, or receiver(s) under decree of any court owning or controlling one or more establishment.                           |      |
| Product/Process Development                                      | Conceptualization and development of a product prior to the production of the product for customers.  |      |
| Radiation Hardened   | Integrated Circuit products incorporating design features and/or physical characteristics that demonstrate a capability to resist radiation-induced damage from industrial sources, electromagnetic pulses, weapons systems and/or charged particles in space that can damage circuitry and render a device inoperable. Some IC devices in be considered radiation hardened when their total dose failure level exceeds >300 krad.[3] A total dose failure level foots the standard cited in International Traffic in Arms (ITAR) regulations.[4]           | nay  |

|                                | OMB 0694-0119 ROCIS Submission  |
|--------------------------------|---|
| Radiation Tolerant             | Integrated Circuit products incorporating design features and/or physical characteristics with limited capability to resist radiation induced damage from industrial sources, electromagnetic pulses, industrial sources, weapons systems, and charged particles in space that can damage circuitry and render a device inoperable. Radiation tolerant would cover parts having a total dose failure level >100 krad but less than 300 krad.  |
| Research and Development       | Basic and applied research in the engineering sciences, as well as design and development of prototype products and processes.  |
| Semiconductor                  | Elemental materials such as silicon and germanium (or compounds like gallium arsenide) that possess levels of electrical conductivity that are less than a conductor but greater than an insulator. The properties of these materials and similar ones can be manipulated to affect conductivity through temperature and/or the use of dopants.   |
| Service                        | An intangible product (contrasted to a good, which is a tangible product). Services typically cannot be stored or transported, are instantly perishable, and come into existence at the time they are bought and consumed.  |
| Single-Event Effects Resistant | Single-event effects caused by a single energetic particle striking an Integrated Circuit (IC) device. Performance of the IC device is not compromised to a point where it is inoperable or not reliable for executing a mission as a result of latch-up, burnout, or gate rupture.   |
| Single Source                  | An organization that is designated as the only accepted source for the supply of parts, components, materials, or services, even though other sources with equivalent technical know-how and production capability may exist.   |
| Sole Source                    | An organization that is the only source for the supply of parts, components, materials, or services. No alternative U.S. or non-U.S. based suppliers exist other than the current supplier.   |
| Supplier                       | An entity from which your organization obtains inputs. A supplier may be another firm with which you have a contractual relationship, or it may be another facility owned by the same parent organization. The inputs may be goods or services.   |
| Trusted Access Program         | A program implemented by the National Security Agency and the Defense Microelectronics Activity (DMEA) to qualify Integrated Circuit design and manufacturing companies as "trusted" suppliers of application specific Integrated Circuit (ASIC) products required for national security applications.  |
| United States                  | The "United States" or "U.S." includes the 50 states, Puerto Rico, the District of Columbia, the island of Guam, the Trust Territories, and the U.S. Virgin Islands.  |
| Wafer Starts Per Week          | The number of semiconductor wafers that can be processed by an Integrated Circuit production line(s) in a 7-day period.   |
|                                | [1] Complimentary metal oxide semiconductor (CMOS) is a class of semiconductor used in digital logic circuits employed in microcontrollers, microprocessors, memory, and other devices. The technology also is used in analog circuits in sensors, transceivers, data converters and other systems.   |
|                                | [2] Sandia National Laboratories. A minority carrier device is a device in which current is conducted by charge carriers of sign (positive or negative) opposite to the dopant polarity of the underlying semiconductor material. In other words, current carried by electrons (negative) in a p-type semiconductor, or by holes in an n-type semiconductor. In semiconductors, minority charge carriers are less abundant than majority charge carriers. Minority carrier devices: Bipolar junction transistors, charge-coupled devices (CCDs), solar cells. |
|                                | [3] Sandia National Laboratories.   |
|                                | [4] ITAR Part 121 – The United States Munitions List (See www.pmddtc.state.gov/consolidated_itar.htm. [Microelectronic circuits are considered radiation hardened when they exceed all five of these standards: (1) Total dose of 5x105 Rads (Si); (2) Dose rate upset of 5x108 Rads (Si) per second; (3) Neutron dose of 1x1014 N/cm2; (4) Single-Event upset of 1x10minus;7 or less error/bit/day; and (5) Single-Event latch-up free and having a dose rate latch-up of 5x108 Rads (Si) per second or greater.]  |
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## CORPORATE LEVEL RESPONSE

# Section III: Organization Reporting Profile

This survey consists of sections that must be answered at the Corporate Level and other sections that must be answered at the Facility Level. The reporting level will be specified at the top of each section in RED. Facilities that will be responding separately from their corporate headquarters should proceed to section 1a to begin the survey.

| from their o | corporate neadquart                             | ers snoula proceed         | to section 1a to beg          | in the survey.  |                          |                        |
|--------------|---|----------------------------|-------------------------------|---|--------------------------|------------------------|
|              |   |                            | escription of Busin           | <u> </u>  |                          |                        |
|              | Select the description its business:            | on of your organizati      | ion's U.S. operations         | s that that most close  | ely reflects             |                        |
|              | Design Integrated C                             | Circuit products (fable    | ess)                          |   |                          | Yes/No                 |
|              | Design and Manufa                               | cture Integrated Circ      | cuit products (integra        | ated device manufac   | cturer)                  |                        |
|              | Design and Manufa                               | cture Integrated Circ      | cuit products; and pe         | erform Package, Tes   | st & Assembly            |                        |
| A.           | Manufacture Integra                             | ated Circuit products      | (as a foundry)                |   |                          |                        |
|              | Manufacture Integra                             | ated Circuit products      | (as a foundry) and            | perform Package, T  | est & Assembly           |                        |
|              | Design Integrated C                             | Circuit products (fable    | ess); and perform P           | ackage, Test & Asse   | embly                    |                        |
|              | Provide Package, T                              | est & Assembly Ser         | vices                         |   |                          |                        |
|              | Other [Write In]                                |                            |                               |   |                          |                        |
|              | Identify the number                             | of Integrated              | IC A                          | ctivity   | U.S.<br>Locations        | Non-U.S.<br>Locations  |
|              | Circuit-related design                          | gn and                     | Design                        |   |                          |                        |
| B.           | manufacturing facility                          |                            | Manufacturing                 |   |                          |                        |
|              | States in 2016.                                 |                            | Packaging, Test<br>& Assembly |   |                          |                        |
|              | Comn  | nents:                     |                               |   |                          |                        |
|              | Identify all of your o the United States.       | rganization's Integra      | ated Circuit-related [        | Design, Manufacturir  | ng, and Packaging fa     | cilities* located in   |
|              | Facility* Name                                  | City                       | State                         | DMEA<br>Certified<br>Trusted** Facility                         | _                        | / Scope<br>Vork        |
|              |   |                            |                               | Yes   | Design                   |                        |
|              |   |                            |                               | No  | Manufacturing            |                        |
|              |   |                            |                               |   | PT&A                     |                        |
|              |   |                            |                               |   | Other                    |                        |
| _            |   |                            |                               |   |                          |                        |
| C.           |   |                            |                               |   |                          |                        |
|              |   |                            |                               |   |                          |                        |
|              |   |                            |                               |   |                          |                        |
|              |   |                            |                               |   |                          |                        |
|              |   |                            |                               |   |                          |                        |
|              |   |                            |                               |   |                          |                        |
|              |   | sembly operations must     | be identified separately.     | as a unified design, fabri<br>Individual wafer fabricati<br>is. |                          |                        |
|              | ** "Trusted" refers to cer<br>Circuit products. | tification from the Defens | se Microelectronics Activ     | ity's Trusted Accredidatio                                      | n Program to design or m | nanufacture Integrated |
| C            | Comments:                                       |                            |                               |   |                          |                        |
|              | BUSIN   | ESS CONFIDENTIA            | L - Per Section 70            | 5(d) of the Defense   | Production Act           |                        |

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|              |   | C                       | ORPORATE LEVEL RESP                         | PONSE   |   |                    |
| Section III: | : Reporting Level (Cont.)   |                         |   |   |   |                    |
| A.           | Is your organization publicly traded                                | or privately held?      |   | If your organization is its stock ticker symbol | publicly traded, identify<br>l.           |                    |
|              | Provide the following identification                                | codes, as applicable, f | for your organization.                      |   |   |                    |
| B.           | Data Universal<br>Numbering System<br>(DUNS) Code(s)                |                         | Harmonized Tariff<br>Schedule (HTS) Code(s) |   | NAICS (6-digit) Code(s)*                  |                    |
|              | Find DUNS numbers at:   |                         | Find NAICS codes at:                        |   |   |                    |
|              | http://fedgov.dnb.com/w<br>ebform                                   |                         | http://hts.usitc.gov                        |   | http://www.census.gov/epcd/www/naics.html |                    |
|              | Indicate if your organization qualifie                              |                         |   |   |   |                    |
|              | A small business enterprise (as de                                  | •                       | ,   |   |   |                    |
|              | 8(a) Firm (as defined by the Small                                  |                         | on)   |   |   |                    |
| C.           | A historically underutilized busines                                | s zone (HUB Zone)       |   |   |   |                    |
|              | A minority-owned business   |                         |   |   |   |                    |
|              | A woman-owned business  |                         |   |   |   |                    |
|              | A veteran-owned or service-disable                                  |                         |   |   |   |                    |
|              | Specify the industry sectors that you located in the United States: | ur organization serves  | s through the provision of de               | esign and/or manufactu                          | uring services for Integrate              | d Circuit products |
|              | Aviation systems/Avionics   | Yes                     | Healthcare/Medical Devic                    | es  |   |                    |
| D.           | Automotive  | No                      | Industrial                                  |   |   |                    |
| D.           | Consumer electronics  | N/A                     | Military and Space                          |   |   |                    |
|              | Communications  |                         | Other National Security sy                  | ystems  |   |                    |
|              | Electronic Data Processing  |                         | Optical/Photonics                           |   |   |                    |
|              | Energy  |                         | Other [Write In]                            |   |   |                    |
|              | Comments:   |                         |   |   |   |                    |
|              | BU  | SINESS CONFIDENT        | TAL - Per Section 705(d) o                  | of the Defense Produc                           | ction Act                                 |                    |

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|             |   | FACILIT             | Y LEVEL RESPON       | SE                        |  |                    |  |  |  |
|             | a: Organization Information                                   |                     |                      |                           |  |                    |  |  |  |
|             | y consists of sections that must be answered at the Corpor    | ate Level and other | er sections that mus | st be answered at the     | e Facility Level. The reporting level will be      | e specified at the |  |  |  |
| top of each | section as appropriate.                                       |                     |                      |                           |  |                    |  |  |  |
|             | Provide the following information for your facility.          |                     |                      |                           |  |                    |  |  |  |
|             | Facility Name   |                     |                      |                           |  |                    |  |  |  |
|             | Street Address  |                     |                      |                           |  |                    |  |  |  |
|             | City  |                     |                      |                           |  |                    |  |  |  |
| A.          | State   |                     |                      |                           |  |                    |  |  |  |
|             | Zip Code  |                     |                      |                           |  |                    |  |  |  |
|             | Website   |                     |                      |                           |  |                    |  |  |  |
|             | Phone Number  |                     |                      |                           |  |                    |  |  |  |
|             | CAGE Code (if applicable)                                     |                     |                      |                           |  |                    |  |  |  |
|             |   | Primary             | / Business           |                           | nductor product design facility                    |                    |  |  |  |
|             | Select the option that most closely describes this facility's | •                   | , Buointoco          |                           | conductor product fabrication facility             |                    |  |  |  |
| В.          | Primary Business, and indicate any "Additional Business       |                     | Business Line        |                           | nductor product packaging, assembly, and test faci | lity               |  |  |  |
| Б.          | Lines."   | / taditional        | Buoinoco Emo         | Integrated circuit/semico | nductor product research and development facility  |                    |  |  |  |
|             |   | Additional          | Business Line        |                           | nductor product corporate headquarters facility    |                    |  |  |  |
|             |   |                     |                      | N/A                       |  |                    |  |  |  |
|             | Provide the following information for your parent organiza    |                     | <u> </u>             |                           |  |                    |  |  |  |
|             |   |                     | Parent Organization  | n 1                       | Parent Organization 2                              | )                  |  |  |  |
|             | Organization Name   |                     |                      |                           |  |                    |  |  |  |
| C.          | Street Address  |                     |                      |                           |  |                    |  |  |  |
| О.          | City  |                     |                      |                           |  |                    |  |  |  |
|             | State/Province  |                     |                      |                           |  |                    |  |  |  |
|             | Country   |                     |                      |                           |  |                    |  |  |  |
|             | Postal Code/Zip Code  |                     |                      |                           |  |                    |  |  |  |
|             | Point of Contact regarding this survey:                       |                     |                      |                           |  |                    |  |  |  |
| D.          | Name  | Title               | Phone                | Number                    | E-mail Address                                     | State              |  |  |  |
|             |   |                     |                      |                           |  |                    |  |  |  |
|             | Comments:   |                     |                      |                           |  |                    |  |  |  |
|             |   |                     |                      |                           |  |                    |  |  |  |
|             | BUSINESS CON  | FIDENTIAL - Per     | Section 705(d) of t  | he Defense Produc         | tion Act   |                    |  |  |  |

Next Page Integrated Circuit Design & Manufacturing 2.a List this facility's Integrated Circuit Design and Manufacturing product capabilities and market types in the United States in calendar year 2016. Design and Manufacturing Facility Market Types and Capabilities Conventional Integrated Circuit Products **Product Capabilities** Single-Event Effects Resistant Radiation Hardened **Neutron Hardened** Market Types Design/Manufacture/Both/Neither 2.b Identify this facility's Integrated Circuit-related design and manufacturing capabilities by technology node, wafer size, and material type Capability to Design and/or Manufacture - by Technology Node, Wafer Size & Material Type (Select all that apply -- A blank response is counted as "No Capability") Technology Node -- by Wafer Carbon Based Technologies (e. nanotubes) Aluminum ( Arsenide Capability [nanometers] 2- or 3-inch 4-inch esign - Radiation Resistant 6-inch Manufacture - Conventional 8-inch 12-inch Both - Design Comments:

tote: 10,000 nanometers equals 10 micrometers 'Respond to this specification if your organization expects to develop a capability to work at this Technology Node by 2021.

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|  |   |                    |                       |                  |  |  |                      | CORPORA       | TE LEVEL F              | RESPONSE             |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
|--|---|--------------------|-----------------------|------------------|--|--|----------------------|---------------|-------------------------|----------------------|------------------------|--------------------|------------------------------|---------------------|--------------------|---------------------|-------------|-------------------------|---|------------------------------|
| Section 2 Integral 2.c Specify your organization's design and specify your organization and specific properties. | rated Circuit<br>ign and manu   |                    |                       |                  |  | o the produc   | tion of custo        | m radiation-t | olerant, radia          | ation-harden         | ed, and neu            | ron hardene        | d Integrated                 | Circuit prod        | ucts located       | in the United       | States:     |                         |   |                              |
|  |   |                    |                       |                  |  |  |                      | Canability    | to Dooign o             | nd/or Monus          | facture by             | Davisa 9 M         | eterial Type                 |                     |                    |                     |             |                         |   |                              |
|  | Capability to Design and/or Manufacture - by Device & Material Type  (Select all that apply A blank response is counted as "No capability") |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| Device Type  | Conventiona IC<br>Products  | Radiation Tolerant | Radiation<br>Hardened | Neutron Hardened | Single-Event<br>Effects Resistant -<br>Destructive | Single-Event<br>Effects Resistant -<br>Non-Destructive | Amorphous<br>Silicon | Bulk Silicon  | Silicon on<br>Insulator | Silicon<br>Germanium | Silicon on<br>Sapphire | Silicon<br>Carbide | Aluminum Gallium<br>Arsenide | Gallium<br>Arsenide | Gallium<br>Nitride | Indium<br>Phosphate | Antimonides | Organic<br>Technologies | Carbon Based<br>Technologies (e.g.,<br>nanotubes) | Superconducting<br>Materials |
| Analog/Linear Technologies   | Design  |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | ĺ                            |
| Digital Logic Technologies   | Manufacture   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | 1                            |
| Digital Signal Processors  | Both  |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| Field Programmable Gate Arrays   | Neither   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| One-time, Electrically Programmable Gate<br>Arrays   |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| Mask Programmable Gate Arrays  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| Structured ASICs [a.k.a. Structured Arrays;<br>Platform ASICs]   |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| Standard Cell ASICs [a.k.a. cell-based ASICs]  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| Custom ASICs   |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| MMIC** Technologies  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u></u>                      |
| Mixed Signal Technologies  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u></u>                      |
| Processors   |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u></u>                      |
| Nonvolatile Memory   |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| 3-D Nonvolatile Memory   |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u></u>                      |
| SRAM   |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u></u>                      |
| DRAM - DDR3  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u></u>                      |
| DRAM - DDR4  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u></u>                      |
| IR*-Focal Plane Arrays   |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u> </u>                     |
| Anti-Tamper Technology   |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u></u>                      |
| Display Electronics  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u></u>                      |
| MEMS Technologies  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   | <u></u>                      |
| Optical/Photonic Technologies  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| RF Technologies  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| Other: [Write In]  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
| Comments:  |   |                    |                       |                  |  |  |                      |               |                         |                      |                        |                    |                              |                     |                    |                     |             |                         |   |                              |
|  |   |                    |                       |                  |  | BUSINES  | S CONFIDE            | NTIAL - Per   | Section 705             | (d) of the D         | efense Proc            | luction Act        |                              |                     |                    |                     |             |                         |   |                              |

OMB 0694-0119 ROCIS Submission revious Page Table of Contents FACILITY LEVEL RESPONSE Section 2 Integrated Circuit Design & Manufacturing - Continued 2.d Identify this facility's design and manufacturing capabilities with regard to the production of Nonvolatile Memory devices, memory density, and access time: Note: Do not complete this page if your organization does not design Nonvolatile Memory products. Proceed to Section 3 Capability to Design Nonvolatile Memory - by Device, Density, Read-Write Speed **Access Time Memory Density** Write/Erase [Nano Seconds (ns)] **Memory Device Type** Select all that apply - A blank response is counted as "No capability" Select all that apply -- A blank response is counted as "No capability" [Provide specifications] (Stand-Alone) Time Size 100-700ps -300 -Specify data 300ps <1ns 1-<10ns 10-<20ns 20-<50ns 50-<150ns >150ns size: Word, (Write in <700ps <128 <32 page, block, Spec.) etc. Erasable Programmable Read-Only Memory (EPROM) Design Write In Write In Electrically Erasable Programmable Read-Only Memory (EEPROM) Manufacture lash - NOR\* Both Flash - NAND Neither lash - NAND 3D\*\* Ferro Electric (FeRAM) Magnetoresistive (MRAM) MEMS-base (nanotube, NRAM) Memristor\*\*\* Phase Change Memory (PCM, a.k.a. PRAM) Polymer Storage Class Memory (e.g., RRAM) Super Permanent Memory (XPM) Zero Capacitor (ZRAM) Other [Write In] Other [Write In] NOR Flash memory is able to read individual flash memory cells, and as such it behaves like a traditional read-only memory (ROM).

\*Nonvolatile random access memory that can be erased electronically and rewritten up to 100,000 times.

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<sup>\*\*</sup> A non-volatile memory technology that can change its resistance in varying levels. It can offer resistance in two states for a digital 0 or 1 or to levels in between to go beyond a binary system.

\*\*\* Pico second = 1 trillionith of a second.

|   |                      |              |                         | Oi                   | VID 0094               | -0119 K            |                              | טופפווווטו          | 111                |                     |              |                         |  |                              |
|---|----------------------|--------------|-------------------------|----------------------|------------------------|--------------------|------------------------------|---------------------|--------------------|---------------------|--------------|-------------------------|--|------------------------------|
| Previous Page   |                      |              |                         |                      |                        | ble of Conte       |                              |                     |                    |                     |              |                         |  | Next Page                    |
| Continuo Ded Talament Des   | l I I a mala manad   | Maurinan I   | landanad IC             |                      |                        | LEVEL RE           | SPONSE                       |                     |                    |                     |              |                         |  |                              |
| Section 3 Rad Tolerant, Rad<br>3.a Identify your organization's current of  |                      |              |                         |                      |                        |                    | n design m                   | anufacturin         | a or both for      | each of the         | following ty | nes of Integr           | ated Circuit                                 |                              |
| 3.a Identity your organization's current  | Japaniilies,         | previous ce  | ipabilities art         | u iiiterest iii      | developing             | capabilities       | ii desigii, iii              | anulaciumi          | y or bour for      | each of the         | ionowing ty  | pes or integra          | ateu Oircuit.                                |                              |
|   |                      |              | Curre                   | ntly (in 201         | 7) has                 |                    |                              |                     | Interes            | sted in dev         | eloning car  | pabilities for          | U.S. Gove                                    | rnment                       |
| Type of Integrated C  | ircuit               |              |                         | apabilities          |                        | Had cap            | pabilities 20                | 13-2016             |                    |                     |              |                         |  |                              |
|   |                      |              |                         |                      |                        |                    |                              |                     |                    | nstituting Ca       | apacity      | 1                       | tiating Capa                                 | city                         |
| Radiation Tolerant  |                      |              | Design                  |                      |                        | Design             |                              |                     | Design             |                     |              | Design                  |  |                              |
| Radiation Hardened  |                      |              | Manufacture             |                      |                        | Manufacture        |                              |                     | Manufacture        |                     |              | Manufacture             |  |                              |
| Neutron Hardened  |                      |              | Both                    |                      |                        | Both               |                              |                     | Both               |                     |              | Both                    |  |                              |
| Single-Events Effects Resistant - Destru  |                      |              | Neither                 |                      |                        | Neither            |                              |                     | Neither            |                     |              | Neither                 |  |                              |
| Single-Event Effects Resistant - Nondes<br>Does your organization design or manuf<br>Resistant Integrated Circuits? |                      | ation Tolera | ant, Radiation          | Hardened,            | Neutron Ha             | irdened or S       | ingle-Event                  | Effects             |                    | Yes/No              |              | If no, pr               | roceed to Se                                 | ection 4.                    |
| 3.b Identify your organization's capabilit  | ies to design        | n and/or ma  | anufacture cu           | stom Integr          | ated Circuit           | products tha       | t are Radiat                 | ion Toleran         | t, Radiation I     | Hardened, N         | leutron Har  | dened or Sin            | gle-Event Ef                                 | fects                        |
| Resistant at locations in the United State  | es.                  |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  |                              |
|   |                      |              |                         |                      | Capab                  | ility to Desi      | gn and/or N                  | lanufacture         | e - by Materi      | al Type             |              |                         |  |                              |
|   |                      |              |                         |                      | (Select                | all that apply     | A blank resp                 | onse is coun        | ted as "No cap     | pability")          |              |                         |  |                              |
|   |                      |              |                         |                      |                        |                    | Ē                            |                     |                    |                     |              |                         | (e.g.,                                       | D                            |
|   |                      |              |                         |                      |                        |                    | Aluminum Gallium<br>Arsenide |                     |                    |                     |              | တ္                      | pa<br>s (e                                   | Superconducting<br>Materials |
|   | Amorphous<br>Silicon | u o          | ⊊ .                     | Silicon<br>Germanium | ⊊ n                    |                    | E                            |                     |                    | ate                 | Antimonides  | Organic<br>Technologies | Carbon Based<br>Technologies (<br>nanotubes) | npu s                        |
|   | n rb                 | iii s        | ator                    | nan                  | o no                   | r ge               | nin                          | E pic               | E a                | m gydg              | no no        | in in                   | a du du                                      | aroo<br>rial                 |
|   | o iii                | Bulk Silicon | Silicon on<br>Insulator | Sem Sem              | Silicon on<br>Sapphire | Silicon<br>Carbide | Aluminum<br>Arsenide         | Gallium<br>Arsenide | Gallium<br>Nitride | Indium<br>Phosphate | iţi.         | Prga<br>ech             | Sarb<br>ech<br>ano                           | Supe                         |
|   | 4 0                  | ш            | 0) =                    | 0, 0                 | 0, 0,                  | 0,0                | 4.4                          | 0                   | 02                 |                     | ,            | O F                     | OFL  | 0) 2                         |
| Radiation Tolerant  | Design               |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  |                              |
|   | Manufacture          |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  |                              |
| Radiation Hardened  |                      |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  |                              |
| Neutron Hardened  | Both                 |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  |                              |
| Single-Event Effects Resistant Destructive  | Neither              |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  |                              |
| Single-Event Effects Resistant - Non-Destructive  |                      |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  |                              |
|   |                      |              |                         |                      |                        | -4                 |                              | -1-104 - 4          | -:-+               |                     |              |                         | in - d \ f=                                  |                              |
| Radiation Tolerant: Integrated circuit prindustrial sources, electromagnetic pulse                                  |                      |              |                         |                      |                        |                    |                              |                     |                    |                     | i induced da | amage (ioniz            | ing dose) iro                                | om                           |
| Radiation Hardened: Integrated circuit  | products inc         | corporating  | design featur           | es and/or p          | hysical char           | acteristics th     | at demonstr                  | rate a capal        | oility to resist   | effects from        | radiation-i  | nduced dama             | age (ionizing                                | dose)                        |
| from industrial sources, electromagnetic  |                      |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  | ,,                           |
|   | <u> </u>             |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  |                              |
| Neutron Hardened: Integrated circuit por<br>electromagnetic pulses that accompany                                   |                      |              |                         | s and/or phy         | ysical charac          | cteristics tha     | t can withsta                | and the dam         | naging effects     | s of high-spe       | eed neutron  | s, gamma ra             | ys, and                                      |                              |
| Single-Event Effects (SEE) Resistant  | - Destructiv         | e: Resistan  | nt to effects ca        | aused by a           | single energ           | etic particle      | striking an li               | ntegrated C         | ircuit (IC) de     | vice. Perfori       | mance of th  | e IC device i           | s not compri                                 | omised to                    |
| a point where it is inoperable or not relia<br>(LET) of 80 MeV.cm2/mg.]   | ble for exec         | uting a miss | sion as a resi          | ult of event         | latch-up, bui          | rnout, or gate     | e rupture, or                | snapback.           | [Immune to d       | destructive S       | SEEs up to   | an ion linear           | energy trans                                 | sfer                         |
| Single-Event Effects Resistant - Non-   |                      |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  |                              |
| point where it is inoperable or not reliabl   | e for execut         | ing a missio | on as a result          | or event up          | set, transier          | nt, or function    | nai interrupt.               | . [immune to        | non-aestru         | CTIVE SEES          | s at an LE I | or 30-40 Me             | v.cm 2/mg.]                                  |                              |
| *Organization possesses manufacturing   | process ted          | chnology to  | achieve radia           | ation tolerar        | nce, hardenii          | ng, or neutro      | n hardening                  | J.                  |                    |                     |              |                         |  |                              |
| Comments:   |                      |              |                         |                      |                        |                    |                              |                     |                    |                     |              |                         |  |                              |

Manufacturing Capabilities & Production Rates Does your organization manufacture Integrated Circuits? Yes/No [If no, proceed to section 4c] As 1) State the average manufacturing capacity utilization rates at your U.S. -based fabrication facility for the years 2013-2016. Then, 2) state the maximum number of wafer starts possible per week at your manufacturing facility, 3) state the actual average wafer starts per week at your facility, and 4) indicate whether this facility will be operating through 2021. Average Manufacturing Capacity Utilization Rates Will this Facility Operate Through 2021? 2016 Average Actual Wafer Starts Per Week 2013 2014 2015 2016 Yes/No Normalized to 8-inch wafer equivalents.

"Assumes 7-days-a-week operations.

Note: a 100% utilization rate equals full operation with no downtime beyond that necessary for maintenance

4.b Specify the maximum Wafer Start capacity per week of your facility in 2016 in the United States by technology node, wafer size, and material type. Wafer Starts Per Week by Circuit Technology Node, Wafer Size & Material Type (State your wafer-start-per-week capacity -- A blank response is counted as "No capability") Minimum -- by Wafer Carbon Based Technology Node Capability Silicon Germanit Size [nanometers] 2- or 3-inch Write In # 10,000 6-inch 8-inch Comments Note: 10,000 nanometers equals 10 micrometers "Respond to this specification if your organization expects to develop a capability to work at this Technology Node by 2021.

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|---|-------------------|-----------------|-----------------|---|---------------|------------------|------------------|---|--------------|--------------|-----------------|----------------|-------------------|--------------|------------|-----------|----------|
|   |                   |                 |                 |   |               |                  | FACIL            | ITY LEVEL                                       | RESPONS      | E            |                 |                |                   |              |            |           |          |
| Section 4   | N                 | lask Produ      | ction and C     | Capability                              |               |                  |                  |   |              |              |                 |                |                   |              |            |           |          |
| Does your organ                                       | nization curre    | ently have ca   | aptive, in-ho   | use Integrate                           | ed Circuit m  | ask-making       | capability?      |   | Ye           | s/No         | [If no, proc    | eed to secti   | on 5]             |              |            |           |          |
| 4.c Identify all te                                   | echnology nod     | les (nanomete   | er ranges) fo   | or which vour                           | organization  | is capable of    | f producina n    | nasks at com                                    | panv-owned   | and operate  | d facilities lo | cated in 1) th | ne United Sta     | ates: and 2) | in company | owned and | operated |
| facilities sited at n                                 | ٠,                | •               | 3,              | , | 3             |                  | ,                |   | , ,          |              |                 | , .            |                   | ,            |            |           | .,       |
|   |                   |                 |                 |   |               |                  | Mask Tech        | nology Noc                                      | de (Nanom    | eters)       |                 |                |                   |              |            |           |          |
|   |                   |                 |                 |   | (Sel          | ect all that a   | apply A bl       | ank respons                                     | se is counte | ed as "No Ca | apability")     |                |                   |              |            |           |          |
| Location  | 10000 -<br>6000   | <6000 -<br>3000 | <3000 -<br>1500 | <1000 -<br>800                          | <800 - 500    | <500 - 350       | <350 - 250       | <250 - 180                                      | <180-130     | <130 - 90    | <90 -65         | <65 - 45       | <45-32            | <32-28       | <22-14     | <10-7     | <7       |
| Location  | U.S.              | Non-U.S.        | Both            |   |               |                  |                  |   |              |              |                 |                |                   |              |            |           |          |
| Indicate the perce                                    | entages of you    |                 | Mask Blan       |   | tt mask produ | iction that are  | e fulfilled in-h | ouse and by                                     | external ma  | sk makers.   | Phase-          | -Shift Mask    | Blanks            |              |            |           |          |
| What percent of y mask requirement production perform | its are fulfilled | tion's binary   |                 | louse                                   |               | nal Mask<br>kers | phase-shift      | nt of your org<br>mask require<br>nask producti | ments are    | In-H         | louse           | by Exter       | rnal Mask<br>kers |              |            |           |          |
| production perion                                     | mou.              |                 | U.S.            | Non-U.S.                                | U.S.          | Non-U.S.         | performed:       | lask producti                                   | OII          | U.S.         | Non-U.S.        | U.S.           | Non-U.S.          |              |            |           |          |
|   |                   |                 | %               | %                                       | %             | %                |                  |   |              | %            | %               | %              | %                 |              |            |           |          |
| С   | Comments:         |                 |                 |   |               |                  |                  |   |              |              |                 |                |                   |              |            |           |          |
|   |                   |                 |                 |   |               |                  |                  |   |              |              |                 |                |                   |              |            |           |          |

|  |                  |               |                |                    | OMB 0694-01            | 119 ROCIS Sub      | mission               |                                  |                               |                                  |                               |                                  |  |  |
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| Section 5:   | Performar        | nce of Produc | tion Steps - \ | Wafer Processing & | CORPO  & Die Packaging | DRATE LEVEL RES    | PONSE                 |                                  |                               |                                  |                               |                                  |  |  |
| Does your organization manufac   | cture Integrated | Circuits?     |                |                    |                        | [If no, proceed to | section 6]            |                                  |                               |                                  |                               |                                  |  |  |
| Identify the Integrated Circuit w<br>employs to perform wafer processi |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               | ur organization                  |  |  |
| Wafer Processing and Pack  | caging Stens     | U.S.          | Non-U.S.       | Country/Count      | ries of Company-O      | wned Facilities    | List of Suppliers     |                                  |                               |                                  |                               |                                  |  |  |
| Waler Frocessing and Fast  | aging otops      | 0.0.          | Location       | Country #1         | Country #2             | Country #3         | Equipment Supplier #1 | Equipment Supplier<br>Country #1 | Equipment Supplier<br>#2 Name | Equipment Supplier<br>Country #2 | Equipment Supplier<br>#3 Name | Equipment Supplier<br>Country #3 |  |  |
| Wafer Thinning   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Backgrinding   |                  | Yes/No        | Yes/No         |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Other [Write In]   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Wafer Dicing   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Saw Blade  |                  | Yes/No        | Yes/No         |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Laser Dicing   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Plasma Dicing  |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Other [Write In]   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Interconnects  |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Wired Bonding  |                  | Yes/No        | Yes/No         |                    |                        | <del></del>        |                       |                                  |                               |                                  |                               |                                  |  |  |
| Solder Bumping   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Stud Bumping   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Pillar   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Redistribution Layer Connects  |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Other [Write In]   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Circuit Bonding  |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Direct Die Film (DDF) Attach   |                  | Yes/No        | Yes/No         |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Silver Glass Attach  |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Leaded Solder Attach   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Gold Silicon Eutectic Attach   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Wafer-to-Wafer   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Other [Write In]   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Substrate/Packaging  |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Ceramic  |                  | Yes/No        | Yes/No         |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Organic  |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Through Silicon Via  |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Flexible   |                  |               |                |                    |                        |                    |                       |                                  |                               |                                  |                               |                                  |  |  |
| Other [Write In]   |                  |               |                |                    |                        | <del></del>        |                       |                                  |                               |                                  |                               |                                  |  |  |

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Comments:

#### CORPORATE LEVEL RESPONSE

# Section 6a: On-Die INPUT/OUTPUT Integrated Circuit Devices & Enabling Firmware

State the percentage of Integrated Circuit On-Die Input/Output Controllers and Firmware used by your organization in 2016 that were 1) produced internally at company facilities located in the U.S. and at Non-U.S. company locations; 2) licensed from U.S. companies, and 3) licensed from non-U.S. companies. Secondly, identify the top three non- U.S. suppliers and countries that were sources of these controllers and firmware used in products manufactured by your company in 2016. Select all that apply -- A blank response is counted as "No Capability."

| Company Produced / Licensed On-Die Input/Output Controllers and Firmware    |  |  |                                    |  |                                   |                     | Non-U.S. Countries and Suppliers |                     |            |                     |            |  |  |  |
|---|--|--|------------------------------------|--|-----------------------------------|---------------------|----------------------------------|---------------------|------------|---------------------|------------|--|--|--|
| Type of On-die Hardware Protocol Controller &<br>Firmware Controlled Device | Internally<br>Produced at<br>Company<br>Locations in<br>U.S. | Internally<br>Produced at<br>Company<br>Locations<br>Outside the<br>U.S. | Licensed<br>from U.S.<br>Companies | Licensed<br>from non-<br>U.S.<br>Companies | Total (must<br>add up to<br>100%) | Supplier #1<br>Name | Country #1                       | Supplier #2<br>Name | Country #2 | Supplier #3<br>Name | Country #3 |  |  |  |
| PCI Express - Controller  | %  | %  | %                                  | %  | %                                 |                     |                                  |                     |            |                     |            |  |  |  |
| PCI Express - Firmware  |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Ethernet (1G, 10G, 25G, 100G) - Controller                                  |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Ethernet (1G, 10G, 25G, 100G) - Firmware                                    |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| USB (1.0, 2.0, 3.0) - Controller  |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| USB (1.0, 2.0, 3.0) - <i>Firmware</i>                                       |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| SATA - Controller   |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| SATA - <i>Firmware</i>  |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Thunderbolt - Controller  |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Thunderbolt - Firmware  |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Firewire - Controller   |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Firewire - <i>Firmware</i>  |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Memory - DDR3 and DDR4 - Controller   |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Memory - DDR3 and DDR4 - Firmware   |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| ZigBee - <i>Controller</i>  |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| ZigBee - <i>Firmware</i>  |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Bluetooth - Controller  |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Bluetooth - <i>Firmware</i>   |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| 802.11 - Controller   |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| 802.11 - <i>Firmwar</i> e   |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Other - Controller [Write in]   |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Other - Firmware [Write in]   |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
| Comments:   |  |  |                                    |  |                                   |                     |                                  |                     |            |                     |            |  |  |  |
|   | BUSIN  | ESS CONFID   | ENTIAL - Pe                        |  | (d) of the De                     | fense Produc        | ction Act                        |                     |            |                     |            |  |  |  |

#### CORPORATE LEVEL RESPONSE

Section 6b:

#### Embedded Integrated Circuit Bit Cell and Memory Compiler Intellectual Property Sources

For your analog, Application Specific Integrated Circuit and Field Programmable Gate Array products, state the percentage of embedded Integrated Circuit bit cell and memory compiler intellectual property used by your organization in 2016 that was 1) produced internally at company facilities located in the U.S. and at Non-U.S. company locations; 2) licensed from U.S. companies, and 3) licensed from non-U.S. companies. Secondly, identify the top three non- U.S. suppliers and countries that were sources of bit cell and memory compiler intellectual property used in products manufactured by your company in 2016. Select all that apply -- A blank response is counted as "No Capability."

| Company Produced / Li                | Country and Sources of Bit Cell, Memory Compiler IP          |   |                                    |  |                                   |                     |            |                     |            |                     |            |
|--------------------------------------|--|---|------------------------------------|--|-----------------------------------|---------------------|------------|---------------------|------------|---------------------|------------|
| Type of Memory Device IP             | Internally<br>Produced at<br>Company<br>Locations in<br>U.S. | Internally Produced at Company Locations Outside the U.S. | Licensed<br>from U.S.<br>Companies | Licensed<br>from non-<br>U.S.<br>Companies | Total (must<br>add up to<br>100%) | Supplier #1<br>Name | Country #1 | Supplier #2<br>Name | Country #2 | Supplier #3<br>Name | Country #3 |
| Embedded EEPROM – Bit Cell           | %  | %   | %                                  | %  | %                                 |                     |            |                     |            |                     |            |
| Embedded EEPROM – Memory Compiler    |  |   |                                    |  |                                   |                     |            |                     |            |                     |            |
| Embedded FLASH – Bit Cell            |  |   |                                    |  |                                   |                     |            |                     |            |                     |            |
| Embedded FLASH – Memory Compiler     |  |   |                                    |  |                                   |                     |            |                     |            |                     |            |
| Embedded SRAM – Bit Cell             |  |   |                                    |  |                                   |                     |            |                     |            |                     |            |
| Embedded SRAM – Memory Compiler      |  |   |                                    |  |                                   |                     |            |                     |            |                     |            |
| Embedded DRAM – Bit Cell             |  |   |                                    |  |                                   |                     |            |                     |            |                     |            |
| Embedded DRAM – Memory Compiler      |  |   |                                    |  |                                   |                     |            |                     |            |                     |            |
| Embedded Other – Bit Cell [Write in] |  |   |                                    |  |                                   |                     |            |                     |            |                     |            |
| Embedded Other – Memory [Write in]   |  |   |                                    |  |                                   |                     |            |                     |            |                     |            |
| Comments:                            |  |   |                                    |  |                                   |                     |            |                     |            |                     |            |

BUSINESS CONFIDENTIAL - Per Section 705(d) of the Defense Production Act

# CORPORATE LEVEL RESPONSE Performance of Production Functions for the Design of Integrated Circuits

Section 7a

Answer the questions on this page ONLY if your organization operates design facilities in the United States to produce Integrated Circuit products. If your organization does not operate design facilities in the United States, proceed to Section 7b.

Identify practices from the list below that reflect; 1) your organization's business methods in regard to execution of the eight design functions listed along the top of this page; 2) its practices and plans on outsourcing Integrated Circuit design.

|  |                                 |            |             | Integrated  | Circuit Design        | Functions                     |            |                               |                         |
|--|---------------------------------|------------|-------------|-------------|-----------------------|-------------------------------|------------|-------------------------------|-------------------------|
| Respond to All Questions   | Analog                          | Digital    | RTL Design* | Synthesis** | Physical<br>Layout*** | Functional<br>Verification*** | Simulation | Test Vector<br>Generation**** | Other (Specify<br>Here) |
| In 2016 performed the following Integrated Circuit Design Steps at facilities in the<br>United States that it owns and operates:   | Yes/No/Not<br>Applicable        |            |             |             |                       |                               |            |                               |                         |
| Did not design at its own U.S. facilities, but contracted with other U.Sbased organizations to perform the design tasks at their U.S. facilities.  | Yes/No/Not<br>Applicable        |            |             |             |                       |                               |            |                               |                         |
| <ol><li>For the 2017-2021, my organization expects to retain capability to perform the<br/>following Integrated Circuit design steps at facilities in the United States that it owns<br/>and operates.</li></ol> | Yes/No/Not<br>Applicable        |            |             |             |                       |                               |            |                               |                         |
| <ol> <li>For 2017-2021 period, my organization will secure other U.Sbased vendors to<br/>complete these design steps at their facilities in the United States.</li> </ol>  | Yes/No/Not<br>Applicable        |            |             |             |                       |                               |            |                               |                         |
| <ol><li>Anticipates that the organization's capabilities to perform the following the eight<br/>design steps facilities in the United States will:</li></ol>   | Increase/Decrease/<br>No Change |            |             |             |                       |                               |            |                               |                         |
| Expects that its use of outsourcing in 2017-2021 will:   | Increase/Decrease/<br>No Change |            |             |             |                       |                               |            |                               |                         |
| 7. In 2016, my organization outsourced the following Integrated Circuit design steps<br>to facilities located outside of the United States that it owns and operates:  | Yes/No/Unknown                  |            |             |             |                       |                               |            |                               |                         |
| The following Integrated Circuit design steps were out-sourced in 2016 to non-U.S. companies operating at non-U.S. locations:  | Yes/No/Unknown                  |            |             |             |                       |                               |            |                               |                         |
| <ol><li>The three primary reasons why my organization outsources Integrated Circuit<br/>design steps to non-U's locations are:</li></ol>   |                                 | Reason # 1 |             |             | Reason #2             |                               |            | Reason #3                     |                         |
| 10. In the space provided, identify the top five countries to which your   |                                 | Country #1 |             |             | Country #2            |                               |            | Country #3                    |                         |
| organization outsources Integrated Circuit design:   |                                 |            |             |             | Country #4            |                               |            | Country #5                    |                         |
| Comments:  |                                 |            | •           |             | •                     | •                             |            |                               |                         |

BUSINESS CONFIDENTIAL - Per Section 705(d) of the Defense Production Act

|                      | < Reasons for Outsourcing |                               |  |  |  |  |  |  |  |  |  |
|----------------------|---------------------------|-------------------------------|--|--|--|--|--|--|--|--|--|
| ariff avoidance      | Lower costs               | Joint venture                 |  |  |  |  |  |  |  |  |  |
| roximity to customer | Market access             | Availability of skilled labor |  |  |  |  |  |  |  |  |  |
| Sovernment subsidies | Production efficiency     | Other                         |  |  |  |  |  |  |  |  |  |

CORPORATE LEVEL RESPONSE

#### Section 7b Performance of Production Functions for the Manufacture of Integrated Circuits

Answer the questions on this page ONLY if your organization operates manufacturing facilities in the United States to produce Integrated Circuit products. If your organization does not operate manufacturing facilities in the United States, proceed to Section 7c.

Identify practices from the list below that reflect; 1) your organization's business methods in regard to execution of the eight manufacturing functions listed along the top of this page; 2) its practices and plans on outsourcing Integrated Circuit manufacturing.

|   |                                 |                                       |   | Integrated Circ | cuit Manufactur | ing Functions |           |                            |                         |
|---|---------------------------------|---------------------------------------|---|-----------------|-----------------|---------------|-----------|----------------------------|-------------------------|
| Respond to All Questions  | Mask Making                     | Wafer<br>Manufacturing<br>(Front End) | Wafer<br>Manufacturing<br>( <i>Back End</i> ) | E-Test          | Wafer Sorting   | Dicing        | Packaging | Final Test &<br>Inspection | Other (Specify<br>Here) |
| In 2016 performed the following Integrated Circuit Manufacturing Steps at facilities in the United States that it owns and operates:  | Yes/No/Not<br>Applicable        |                                       |   |                 |                 |               |           |                            |                         |
| <ol><li>Did not manufacture at its own U.S. facilities, but contracted with other U.S<br/>based organizations to perform the manufacturing tasks at their U.S. facilities.</li></ol>                                    | Yes/No/Not<br>Applicable        |                                       |   |                 |                 |               |           |                            |                         |
| <ol><li>For the 2017-2021, my organization expects to retain capability to perform the<br/>following Integrated Circuit manufacturing steps at facilities in the United States that<br/>it owns and operates.</li></ol> | Yes/No/Not<br>Applicable        |                                       |   |                 |                 |               |           |                            |                         |
| For 2017-2021 period, my organization will secure other U.Sbased vendors to complete these manufacturing steps at their facilities in the United States.  | Yes/No/Not<br>Applicable        |                                       |   |                 |                 |               |           |                            |                         |
| 5. Anticipates that the organization's capabilities to perform the following the eight<br>manufacturing steps facilities in the United States will:   | Increase/Decrease/<br>No Change |                                       |   |                 |                 |               |           |                            |                         |
| Expects that its use of outsourcing in 2017-2021 will:  | Increase/Decrease/<br>No Change |                                       |   |                 |                 |               |           |                            |                         |
| 7. In 2016, my organization outsourced the following Integrated Circuit manufacturing steps to facilities located outside of the United States that it owns and operates:   | Yes/No/Unknown                  |                                       |   |                 |                 |               |           |                            |                         |
| The following Integrated Circuit manufacturing steps were out-sourced in 2016 to non-U.S. companies operating at non-U.S. locations:  | Yes/No/Unknown                  |                                       |   |                 |                 |               |           |                            |                         |
| 9. The three primary reasons why my organization outsources Integrated Circuit manufacturing steps to non-U's locations are:  |                                 | Reason # 1                            |   |                 | Reason #2       |               |           | Reason #3                  |                         |
| 10. In the space provided, identify the top five countries to which your  |                                 | Country #1                            |   |                 | Country #2      |               |           | Country #3                 |                         |
| organization outsources Integrated Circuit manufacturing:   |                                 |                                       |   |                 | Country #4      |               |           | Country #5                 |                         |
| Comments:   |                                 |                                       |   |                 |                 |               |           |                            |                         |
| BUSINI  | ESS CONFIDENT                   | TIAL - Per Secti                      | on 705(d) of the                              | e Defense Prod  | luction Act     |               |           |                            |                         |

| < Reasons for Outsourcing |                       |                               |  |  |  |  |  |  |  |  |
|---------------------------|-----------------------|-------------------------------|--|--|--|--|--|--|--|--|
| Tariff avoidance          | Lower costs           | Joint venture                 |  |  |  |  |  |  |  |  |
| Proximity to customer     | Market access         | Availability of skilled labor |  |  |  |  |  |  |  |  |
| Government subsidies      | Production efficiency | Other                         |  |  |  |  |  |  |  |  |

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CORPORATE LEVEL RESPONSE

|   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              | CORPO                        | RATE L             | EVEL R              | RESPON      | ISE                     |   |                              |                |                |                |              |            |            |            |            |           |                    |          |              |               |              | Ш  |
|---|-----------------------------|--------------------|--------------------|------------------|--|---|----------------------|--------------|-------------------------|----------------------|------------------------|--------------------|------------------------------|------------------------------|--------------------|---------------------|-------------|-------------------------|---|------------------------------|----------------|----------------|----------------|--------------|------------|------------|------------|------------|-----------|--------------------|----------|--------------|---------------|--------------|----|
| CORPORATE LEVEL RESPONSE  Section 7c Outsourcing of Production Steps for the Design and Manufacture of Integrated Circuits Specify the characteristics of the Integrated Circuit products for which your organization outsources Design and/or Manufacturing Steps.  If your organization does not outsource Integrated Circuit design or manufacturing facilities in the United States, proceed to Section 8 |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           |                    |          |              |               |              |    |
| The your organization does not outsource Integrated Circuit design or manufacturing facilities in the United States, proceed to  Section 8.  Outsourced Design - by Device Type, Material, & Circuit Technology Node  (Select all that apply A blank response is counted as "No Capability")  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           |                    |          |              |               |              |    |
|   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           |                    |          |              |               |              |    |
|   |                             |                    | Con                | a bilita r       |  |   | 1                    |              |                         |                      |                        |                    |                              | ly A bla<br>r <b>Materia</b> |                    |                     | counted     | as "No C                | Capability  | /")                          | 1              |                |                |              | ivarris    | Took       |            | n. No      | do Inc    |                    | 24272    | ,            | _             |              |    |
|   |                             |                    | Capa<br>_          | ability          | 1  | Ι   |                      | 1            | I                       | 1                    | 1                      | Semico             | naucto                       | r Materia                    | ii rypes           | 1                   | 1           | I                       | I   |                              | 1              |                |                | 1            | Ircun      | recni      | nolog      | y No       | je įna    | anome              | eters    | <del>'</del> | $\overline{}$ |              | -  |
| Device Types  | Conventional IC<br>Products | Radiation Tolerant | Radiation Hardened | Neutron Hardened | Single-Event Effects<br>Resistant -<br>Destructive | Single-Event Effects<br>Resistant - Non-<br>Destructive | Amorphous<br>Silicon | Bulk Silicon | Silicon on<br>Insulator | Silicon<br>Germanium | Silicon on<br>Sapphire | Silicon<br>Carbide | Aluminum Gallium<br>Arsenide | Gallium<br>Arsenide          | Gallium<br>Nitride | Indium<br>Phosphate | Antimonides | Organic<br>Technologies | Carbon Based<br>Technologies (e.g.,<br>nanotubes) | Superconducting<br>Materials | 10,000 - 6,000 | 3,000 - <6,000 | 1,500 - <3,000 | 800 - <1,000 | 500 - <800 | 350 - <500 | 250 - <350 | 130 - <180 | 90 - <130 | 96 30              | 45 - <60 | 32 - <45     | 14 - <22      | 7 - <10      | /> |
| Analog/Linear Technologies  | Design                      |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           |                    |          |              |               |              |    |
| Digital Logic Technologies  | Manufacti                   | ure                |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           |                    |          |              |               |              |    |
| Digital Signal Processors   | Both                        |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           |                    |          |              |               |              |    |
| Field Programmable Gate Arrays  | Neither                     |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           |                    |          |              |               |              |    |
| One-time, Electrically Programmable Gate<br>Arrays  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            | $\perp$    |           | Ш                  |          |              |               |              |    |
| Mask Programmable Gate Arrays   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           | Ш                  |          |              |               |              |    |
| Structured ASICs [a.k.a. Structured Arrays;<br>Platform ASICs]  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           | Ш                  |          |              |               |              |    |
| Standard Cell ASICs [a.k.a. cell-based<br>ASICs]  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            | $\perp$    |           | $\sqcup$           | _        | ᆚ            | ╙             | $oxed{oxed}$ | ╛  |
| Custom ASICs  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           | $\sqcup$           |          | ┵            | ┸             |              | ╛  |
| MMIC** Technologies   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           | $\sqcup$           |          | ┵            | ┸             |              | ╝  |
| Mixed Signal Technologies   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           | $\sqcup$           |          | ┵            | ┸             |              | ╛  |
| Processors  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            | $\perp$    | Ш         | $\perp \perp$      |          |              | ┸             |              |    |
| Nonvolatile Memory  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            | <u> </u>   |           | $\perp \perp$      |          |              | $\perp$       |              |    |
| 3-D Nonvolatile Memory  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            | <u> </u>   |           | $\perp \perp$      |          |              | $\perp$       |              |    |
| SRAM  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            | $\perp$    | Ш         | $\perp \perp$      |          |              | ┸             |              |    |
| DRAM - DDR3   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           | Ш                  |          |              |               |              |    |
| DRAM - DDR4   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            | <u> </u>   |           | $\perp \perp$      |          |              | $\perp$       |              |    |
| IR*-Focal Plane Arrays  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            | Ш         | $\perp \downarrow$ |          |              | $\perp$       | Ш            |    |
| Anti-Tamper Technology  |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            | Ш         | $\perp \downarrow$ |          | $\perp$      | $\perp$       | Ш            |    |
| Display Electronics   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            | Ш         | $\perp \perp$      | $\perp$  |              | $\perp$       | Ш            |    |
| MEMS Technologies   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            | Ш         | Ш                  |          |              |               | Ш            |    |
| Optical/Photonic Technologies   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            | $\perp$    |           | Ш                  |          |              |               | Ш            |    |
| RF Technologies   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           | $\perp \perp$      |          |              | $\perp$       | Ш            |    |
| Other: [Write In]   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           | Ш                  |          | $\perp$      |               |              |    |
| Comments:   |                             |                    |                    |                  |  |   |                      |              |                         |                      |                        |                    |                              |                              |                    |                     |             |                         |   |                              |                |                |                |              |            |            |            |            |           |                    |          |              |               |              |    |
|   |                             |                    |                    |                  |  |   |                      | В            | USINES                  | S CONF               | IDENTI                 | AL - Per           | Section                      | 705(d)                       | of the D           | efense l            | Product     | ion Act                 |   |                              |                |                |                |              |            |            |            |            |           |                    |          |              |               |              | J  |

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|  | C                      | ORPORATE LE             | VEL RESPONSE               |                          |   |
| Section 8a: National Sec   | urity Requireme        | nts - The Trust         | ed Access Prograi          | n                        |   |
| <ol> <li>Does your organization have i<br/>Circuit products in a trusted* env<br/>Defense (DOD) standards for the</li> </ol> | rironment located      | in the United St        |                            |                          | Design/Manufacture/Both/Not<br>Applicable                           |
| 2. Has your organization been co   | ertified by DOD's      | Trusted Access          | Program Office at t        | he Defense               |   |
| Microelectronics Activity (DMEA)   | ) as a 'trusted' su    | pplier of Integrat      | ted Circuit products       | ?                        | Yes/No/Not Applicable   |
| 3. Is your organization planning to Defense Microelectronics Activity  |                        | •                       |                            |                          | Yes/No/Unknown  |
| <b>4.</b> How does your organization v securing accreditation through D  |                        |                         |                            | es incurred for          | Favorably/Unfavorably/No opinion                                    |
| 5. Is your organization familiar w which do you assess most favora   |                        |                         |                            |                          | Unfamiliar/Split<br>Manufacturing/Tiers of<br>Trust/Trust by Design |
| <b>6.</b> If your organization has recen identify the affected facility by na  |                        | -                       | reason for your org        |                          |   |
| Name:  |                        |                         | Address:                   |                          |   |
| Explanation:   |                        |                         |                            |                          |   |
| 7. If you answered "Yes" to Quebeen awarded, (2) the facilities for that facility.   |                        | •                       |                            | ~                        | ` '   |
| Facility Name(s)   | City                   | State                   | Awarded<br>Certification   | Seeking<br>Certification | Business Activity   |
|  |                        |                         | Yes/No                     | Yes/No                   | Design  |
|  |                        |                         |                            |                          | Manufacture   |
|  |                        |                         |                            |                          | Package, Test, Assembly   |
|  |                        |                         |                            |                          |   |
|  |                        |                         |                            |                          |   |
| Comments:  |                        |                         |                            |                          |   |
| * "Trusted" refers to certification from the D   | efense Microelectronic | cs Activity's Trusted A | Accreditation Program to d | esign or manufacture I   | ntegrated Circuits.   |
| BUSINES  | SS CONFIDENTI          | AL - Per Sectio         | n 705(d) of the Det        | ense Production          | n Act   |

**CORPORATE LEVEL RESPONSE** 

Section 8b National Security Requirements - Outlook on Future Capability to Supply Integrated Circuit Products
For each of the Integrated Circuit devices listed, indicate 1) how your organization's ability to design and/or manufacture at its United States facilities may change in the next five years. 2) State the primary factor contributing to this change (if applicable); and 3) Identify the types of customers that would be affected by this change.

| affected by this change.                                       |                   |                                |                                |                          |                       |                             |
|--|-------------------|--------------------------------|--------------------------------|--------------------------|-----------------------|-----------------------------|
|  |                   | (Select all that a             | pply A blank resp              | oonse is counted as      | "No Capability")      |                             |
| Device Types   | Inte              | egrated Circuit Des            |                                | Integra                  | ted Circuit Manufa    |                             |
|  | Future Capability | Primary Factor                 | Types of Affected<br>Customers | Future Capability        | Primary Factor        | Types of Affected Customers |
| Analog/Linear Technologies                                     |                   |                                |                                |                          |                       |                             |
| Digital Logic Technologies                                     | Increase          | Labor costs                    | Commercial (COTS stan          | ndard Products)          |                       |                             |
| Digital Signal Processors                                      | Decrease          | Cost of Modernization          | Commercial(Custom Pro          | oducts)                  |                       |                             |
| Field Programmable Gate Arrays                                 | Cease             | Low order volume               | Industrial (COTS standa        | ard Products)            |                       |                             |
| One-time, Electrically Programmable Gate<br>Arrays             | No Change         | ,                              | Industrial(Custom Produ        | ucts)                    |                       |                             |
| Mask Programmable Gate Arrays                                  | N/A               | Meeting DOD<br>Requirements    | U.S. Government Agend          | cies - excluding DOD (Cu | stom Products)        |                             |
| Structured ASICs [a.k.a. Structured Arrays;<br>Platform ASICs] |                   | Regulations                    | DOD (Custom Products)          | )                        |                       |                             |
| Standard Cell ASICs [a.k.a. cell-based ASICs]                  |                   | Technology lag                 | DOD (COTS standard P           | Products)                |                       |                             |
| Custom ASICs   |                   | Low Profitability              | DOD (Custom Products)          | )                        |                       |                             |
| MMIC** Technologies  |                   | Trusted Certification<br>Costs | U.S. Government Agend          | cies - excluding DOD CO  | TS standard Products) |                             |
| Mixed Signal Technologies                                      |                   | Rising Commercial<br>Orders    |                                |                          |                       |                             |
| Processors   |                   | Rising US Government<br>Orders |                                |                          |                       |                             |
| Nonvolatile Memory   |                   | Design Difficulty              |                                |                          |                       |                             |
| 3-D Nonvolatile Memory   |                   |                                |                                |                          |                       |                             |
| SRAM   |                   |                                |                                |                          |                       |                             |
| DRAM - DDR3  |                   |                                |                                |                          |                       |                             |
| DRAM - DDR4  |                   |                                |                                |                          |                       |                             |
| IR*-Focal Plane Arrays   |                   |                                |                                |                          |                       |                             |
| Anti-Tamper Technology   |                   |                                |                                |                          |                       |                             |
| Display Electronics  |                   |                                |                                |                          |                       |                             |
| MEMS Technologies  |                   |                                |                                |                          |                       |                             |
| Optical/Photonic Technologies                                  |                   |                                |                                |                          |                       |                             |
| RF Technologies  |                   |                                |                                |                          |                       |                             |
| Other [Write In]   |                   |                                |                                |                          |                       |                             |
| Comments:  |                   |                                |                                |                          |                       |                             |
| Е  | SUSINESS CONFID   | ENTIAL - Per Sect              | ion 705(d) of the D            | efense Production        | Act                   |                             |

CORPORATE LEVEL RESPO

| Section 9:  |                      |                      | nent Supplie         |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
|---|----------------------|----------------------|----------------------|--|-----------------------------|---------------|---------------|----------------|--|-----------------------------|---------------|--------------|----------------|--|-----------------------------|--------------|---------------|---------------|--|
| For each of the listed processes, identify those used by y<br>three. A blank response will be counted as "no capability | our organiza<br>."   | tion by 1) W         | riting in princ      | ipal equipment   | type 2) Prim                | nary practice | for maintain  | ing equipme    | nt and 3) yo                           | ur organizati               | on's three pr | imary suppli | ers of that ed | quipment. If                           | you only have               | e one suppli | er, enter "No | one" for supp | liers two and                          |
|   |                      |                      |                      |  |                             |               |               |                |  | quipment S<br>By Process    |               |              |                |  |                             |              |               |               |  |
|   |                      |                      |                      |  |                             |               | (Selec        | t all that app |  | response is                 |               | "No Capabil  | ity")          |  |                             |              |               |               |  |
| Integrated Circuit Manufacturing<br>Processes - Front to Back   | Type of Equipment #1 | Type of Equipment #2 | Type of Equipment #3 | Primary Company Practice - Equipment Maintenance Performed By: | Equipment<br>Supplier<br>#1 | City          | State         | Country        | Single or<br>Sole<br>Source<br>Suppler | Equipment<br>Supplier<br>#2 | City          | State        | Country        | Single or<br>Sole<br>Source<br>Suppler | Equipment<br>Supplier<br>#3 | City         | State         | Country       | Single or<br>Sole<br>Source<br>Suppler |
| Wet Wafer Cleaning  | Write In             |                      |                      | Company employ   | ees                         |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Piranha solution  |                      |                      |                      | Manufacturer   |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| RCA clean   |                      |                      |                      | OEM Distributor  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Photolithography  |                      |                      |                      | Third-Party Contra   | actor                       |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Ion implantation  |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Dry etching   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Wet etching   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Plasma strip/Ashing   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Thermal treatments Rapid thermal anneal   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Furnace anneals   |                      |                      | İ                    |  |                             |               | İ             |                |  |                             |               |              |                |  |                             |              |               | İ             |  |
| Furnace Thermal oxidation   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Rapid thermal oxidation   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Epitaxy   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Chemical vapor deposition (CVD)   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Plasma enhanced chemical vapor deposition (PECVD)   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Rapid thermal chemical vapor deposition   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Physical vapor deposition (PVD)   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Molecular beam epitaxy (MBE)  |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Electrochemical deposition (ECD)  |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Chemical-mechanical planarization (CMP)   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Inline monitor testing at wafer level<br>[interstitial/ silver /kerf structures]  |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Wafer bumping (flip chip products only)   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Through silicon via (TSV), back side thinning and backside metal redistribution [if a 3-D chip]                         |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Wafer functional test (testing of design structures)  |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Wafer backgrinding (Smartcard, PCMCIA cards, other applications)  |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Die preparation Wafer mounting / Tape   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Die cutting/dicing  |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| IC packaging Die attachment/bonding   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| IC bonding Wire bonding (if wirebond product)   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Thermosonic bonding   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Wafer bonding (if a wafer level bonded assembly)  |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Tape Automated Bonding (TAB)  |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| IC encapsulation Baking   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Plating   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Laser marking   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Trim and form   |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| IC testing  |                      |                      |                      |  |                             |               |               |                |  |                             |               |              |                |  |                             |              |               |               |  |
| Comments:   |                      |                      | · · ·                | 511  | CINECO CO                   | UEIDENT' A    | Dan Carati    | 705(-1)        | 23                                     | - Dandard                   | - 1-1         |              |                |  |                             |              |               |               |  |
|   |                      |                      |                      | BUS  | SINESS COM                  | NEIDENTIA     | L - Per Secti | on /U5(d) o    | the Detens                             | e Productio                 | n ACt         |              |                |  |                             |              |               |               |  |

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|-----------------|---|--|-----------------------------|---|---|--------------------|-----------------|--|---|-------------------|
|                 |   |  |                             | FACILITY  | LEVEL RE  | SPONSE             |                 |  |   |                   |
| Section 1<br>A. | Indicate th   | Employment<br>be primary Integrated Cir<br>actors at this facililty:   |                             |   |   |                    |                 |  | Design/Manufacture/F<br>Assembly  | •                 |
|                 |   | total number of full time ed<br>ot double count personnel  |                             |   |   |                    | J.S./domestic   | operations b   | y labor type for cale   | ndar years 2013-  |
|                 |   |  | Schedule:                   |   | ,   |                    | alendar Yea     | ar/Fiscal Ye   | ar  |                   |
| _               |   |  |                             |   |   | 2013               | 2014            | 2015   | 2016  |                   |
| B.              | 1   | FTE Employees  |                             |   |   |                    |                 |  |   |                   |
|                 | 2   | FTE Contractors  |                             |   |   |                    |                 |  |   |                   |
|                 | 3   | Number of US Citizens  |                             |   |   |                    |                 |  |   |                   |
|                 | 4   | Number of non-US Citi  |                             |   |   |                    | 11.0            |  |   |                   |
|                 |   | o five countries (other the number of each type of   |                             | en card hol   | der associat  | ted with ead       | ch country.     |  |   |                   |
|                 |   | Country  |                             | H-1B  | H-2B  | F                  | -1              |  |   | al (Auto Sum)     |
| C.              |   |  |                             | #   | #   |                    |                 | 7  | #   | #                 |
| О.              |   |  |                             |   |   |                    |                 |  |   |                   |
|                 |   |  |                             |   |   |                    |                 |  |   |                   |
|                 |   |  |                             |   |   |                    |                 |  |   |                   |
|                 | Circuit pro   | duct manufacturing (fab  | rication). Bl               | lanks will be   | interpreted   | l as meanin        | g that there    | are no pers  | sonnel on site at th  | is facility       |
|                 | performing<br>Occup   | the listed job function.   | Number of Staff             | Occup   | eational Cate   | egory -            | Number of Staff |  | pational Category -<br>acture of Integrated   | Number of         |
|                 | performing<br>Occup<br>Design   | g the listed job function. pational Category - of Integrated Circuits  | Number of                   | Occup<br>Manufa   | pational Cate<br>acture of Inte<br>Circuits   | egory -            | Number of       | Manufa   | pational Category -<br>acture of Integrated<br>Circuits   | Number of         |
|                 | Occup<br>Design<br>Silicon Design   | g the listed job function. pational Category - of Integrated Circuits  | Number of                   | Occup<br>Manufa<br>Environmenta   | pational Cate<br>acture of Inte<br>Circuits<br>al Engineering   | egory -            | Number of       | Manufa Engineering N   | pational Category -<br>acture of Integrated<br>Circuits<br>Manager  | Number of         |
|                 | performing<br>Occup<br>Design   | g the listed job function.  pational Category - of Integrated Circuits   | Number of                   | Occup<br>Manufa<br>Environmenta<br>Safety Engine  | pational Cate<br>acture of Inte<br>Circuits<br>al Engineering<br>eer  | egory -<br>egrated | Number of       | Manufa Engineering Manufacturing   | pational Category -<br>acture of Integrated<br>Circuits<br>Manager<br>g Manager   | Number o          |
|                 | Occup<br>Design<br>Silicon Desig<br>Researcher<br>Quality Engir   | g the listed job function.  pational Category - of Integrated Circuits   | Number of                   | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc   | pational Cate<br>acture of Inte<br>Circuits<br>al Engineering   | egory -<br>egrated | Number of       | Manufa Engineering N Manufacturing Facilities Engi   | pational Category -<br>acture of Integrated<br>Circuits<br>Manager<br>g Manager<br>ineering/Technician  | Number o          |
|                 | Occup<br>Design<br>Silicon Desig<br>Researcher<br>Quality Engir<br>Pre Silicon V  | g the listed job function. pational Category - of Integrated Circuits an Architect   | Number of                   | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician   | pational Cate<br>acture of Inte<br>Circuits<br>al Engineering<br>eer  | egory -<br>egrated | Number of       | Manufa Engineering N Manufacturing Facilities Engi Shift Manage  | pational Category -<br>acture of Integrated<br>Circuits<br>Manager<br>g Manager<br>ineering/Technician  | Number o          |
| C.              | Occup<br>Design<br>Silicon Desig<br>Researcher<br>Quality Engir<br>Pre Silicon V  | g the listed job function.  pational Category - of Integrated Circuits  In Architect  Integrated Circuits  Integra | Number of<br>Staff          | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician   | pational Cate acture of Inte Circuits al Engineering eer curement/Supp  | egory -<br>egrated | Number of       | Manufa Engineering N Manufacturing Facilities Engi   | pational Category - acture of Integrated Circuits Manager g Manager ineering/Technician r sis Engineer  | Number o          |
| C.              | Occup<br>Design<br>Silicon Desig<br>Researcher<br>Quality Engir<br>Pre Silicon V  | g the listed job function.  pational Category - of Integrated Circuits  In Architect  Pational Category - Of Integrated Circuits  In | Number of<br>Staff          | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engi   | pational Cate acture of Inte Circuits al Engineering eer curement/Supp  | egory -<br>egrated | Number of       | Manufa<br>Engineering M<br>Manufacturing<br>Facilities Engi<br>Shift Manager<br>Failure Analys<br>Integration Er                       | pational Category - acture of Integrated Circuits Manager g Manager ineering/Technician r sis Engineer  | Number o          |
| C.              | Occup Design Silicon Desig Researcher Quality Engir Pre Silicon V Post Silicon V Layout Engir   | g the listed job function.  pational Category - of Integrated Circuits  gn Architect  neers 'alidation Engineer  validation Engineer neer  | Number of<br>Staff          | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engine   | pational Cate acture of Inte Circuits al Engineering eer curement/Supp neer/Technicia   | egory -<br>egrated | Number of       | Manufa<br>Engineering M<br>Manufacturing<br>Facilities Engi<br>Shift Manager<br>Failure Analys<br>Integration Er                       | pational Category - acture of Integrated Circuits  Manager g Manager ineering/Technician r sis Engineer ngineer/Technician  | Number o          |
| C.              | Performing  Occup Design  Silicon Desig Researcher Quality Engin Pre Silicon V Post Silicon V Layout Engin Debug Engin  | g the listed job function.  pational Category - of Integrated Circuits  In Architect  Integrated Circuits  Integra | Number of<br>Staff          | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engin<br>Product Engin   | pational Cate acture of Inte acture | egory -<br>egrated | Number of       | Manufa  Engineering Manufacturing Facilities Engi Shift Manager Failure Analys Integration Er Automation E                             | pational Category - acture of Integrated Circuits  Manager g Manager ineering/Technician r sis Engineer ngineer/Technician ngineer/Technician                     | Number o          |
| C.              | Occup Design Silicon Desig Researcher Quality Engin Pre Silicon V Post Silicon V Layout Engin Debug Engin Electronic Er   | g the listed job function.  pational Category - of Integrated Circuits  In Architect  Integrated Circuits  Integra | Number of<br>Staff          | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engin<br>Product Engin<br>Manufacturing  | pational Cate acture of Inte acture | egory -<br>egrated | Number of       | Manufa  Engineering N Manufacturing Facilities Engi Shift Manager Failure Analys Integration En Automation E Factory Mana              | pational Category - acture of Integrated Circuits  Manager g Manager ineering/Technician r sis Engineer ngineer/Technician ngineer/Technician                     | Number o          |
| C.              | Occup Design Silicon Desig Researcher Quality Engir Pre Silicon V Post Silicon V Layout Engin Debug Engin Electronic Er RF/Analog E   | g the listed job function. pational Category - of Integrated Circuits  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In In Architect  In In Architect  In In Architect  In In In In In In In In In In In In In I   | Number of<br>Staff          | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engin<br>Product Engin<br>Reticle Engine<br>Manufacturing<br>Equipment Er                  | pational Cate acture of Inte acture | egory -<br>egrated | Number of       | Manufa  Engineering N Manufacturing Facilities Engi Shift Manager Failure Analys Integration En Automation E Factory Mana              | pational Category - acture of Integrated Circuits  Manager g Manager ineering/Technician r sis Engineer ngineer/Technician ngineer/Technician                     | Number o          |
| C.              | Occup Design Silicon Desig Researcher Quality Engir Pre Silicon V Post Silicon V Layout Engin Debug Engin Electronic Er RF/Analog E Integration E   | g the listed job function.  pational Category - of Integrated Circuits  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In In Architect  In In Architect  In In Architect  In In In In In In In In In In In In In I  | Number of<br>Staff          | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engin<br>Product Engin<br>Reticle Engine<br>Manufacturing<br>Equipment Er                  | pational Cate acture of Inte acture | egory -<br>egrated | Number of       | Manufa  Engineering N Manufacturing Facilities Engi Shift Manager Failure Analys Integration En Automation E Factory Mana              | pational Category - acture of Integrated Circuits  Manager g Manager ineering/Technician r sis Engineer ngineer/Technician ngineer/Technician                     | Number of         |
| C.              | Performing Occup Design Silicon Desig Researcher Quality Engir Pre Silicon V Post Silicon V Layout Engin Debug Engin Electronic Er RF/Analog E Integration E CAD Engine Thermal Eng Mechanical E  | g the listed job function.  pational Category - of Integrated Circuits  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In In Architect  In In Architect  In In Architect  In In Architect  In In In In In In In In In In In In In I   | Number of<br>Staff          | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engin<br>Product Engin<br>Reticle Engine<br>Manufacturing<br>Equipment Er                  | pational Cate acture of Inte acture | egory -<br>egrated | Number of       | Manufa  Engineering N Manufacturing Facilities Engi Shift Manager Failure Analys Integration En Automation E Factory Mana              | pational Category - acture of Integrated Circuits  Manager g Manager ineering/Technician r sis Engineer ngineer/Technician ngineer/Technician                     | Number o          |
| C.              | Performing Occup Design Silicon Desig Researcher Quality Engir Pre Silicon V Post Silicon V Layout Engin Debug Engin Electronic Er RF/Analog E Integration E CAD Engine Thermal Eng Mechanical E Packaging E  | g the listed job function.  pational Category - of Integrated Circuits  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In In Architect  In In Architect  In In Architect  In In In Architect  In In In In In In In In In In In In In I  | Number of<br>Staff          | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engin<br>Product Engin<br>Reticle Engine<br>Manufacturing<br>Equipment Er                  | pational Cate acture of Inte acture | egory -<br>egrated | Number of       | Manufa  Engineering N Manufacturing Facilities Engi Shift Manager Failure Analys Integration En Automation E Factory Mana              | pational Category - acture of Integrated Circuits  Manager g Manager ineering/Technician r sis Engineer ngineer/Technician ngineer/Technician                     | Number of         |
| C.              | Performing Occup Design Silicon Desig Researcher Quality Engir Pre Silicon V Post Silicon V Layout Engin Debug Engin Electronic Er RF/Analog E Integration E CAD Engine Thermal Eng Mechanical E  | g the listed job function.  pational Category - of Integrated Circuits  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In In Architect  In In Architect  In In Architect  In In In Architect  In In In In In In In In In In In In In I  | Number of<br>Staff          | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engin<br>Product Engin<br>Reticle Engine<br>Manufacturing<br>Equipment Er                  | pational Cate acture of Inte acture | egory -<br>egrated | Number of       | Manufa  Engineering N Manufacturing Facilities Engi Shift Manager Failure Analys Integration En Automation E Factory Mana              | pational Category - acture of Integrated Circuits  Manager g Manager ineering/Technician r sis Engineer ngineer/Technician ngineer/Technician                     | Number o          |
| C.              | Performing Occup Design Silicon Desig Researcher Quality Engir Pre Silicon V Post Silicon V Layout Engin Debug Engin Electronic Er RF/Analog E Integration E CAD Engine Thermal Eng Mechanical E Packaging E Program Mar  | g the listed job function.  pational Category - of Integrated Circuits  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In In Architect  In In Architect  In In Architect  In In In Architect  In In In In In In In In In In In In In I  | Number of Staff  Type of In | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engin<br>Product Engin<br>Reticle Engine<br>Manufacturing<br>Equipment Er                  | pational Cate acture of Inte acture | egory -<br>egrated | Number of       | Manufa  Engineering N Manufacturing Facilities Engi Shift Manager Failure Analys Integration En Automation E Factory Mana              | pational Category - acture of Integrated Circuits  Manager g Manager ineering/Technician r sis Engineer ngineer/Technician ngineer/Technician                     | Number o<br>Staff |
| D.              | Performing Occup Design Silicon Desig Researcher Quality Engir Pre Silicon V Post Silicon V Layout Engin Debug Engin Electronic Er RF/Analog E Integration E CAD Engine Thermal Eng Mechanical E Packaging E Program Mar  State 1) the working at t percentage projected to | g the listed job function.  pational Category - of Integrated Circuits  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In Architect  In In Architect  In In Architect  In In Architect  In In Architect  In In Architect  In In In Architect  In In In Architect  In In In In In In In In In In In In In I  | Number of Staff  Type of In | Occup<br>Manufa<br>Environmenta<br>Safety Engine<br>Planning/Proc<br>Statistician<br>Process Engin<br>Product Engin<br>Reticle Engin<br>Manufacturing<br>Equipment Er<br>Industrial Eng | pational Cate acture of Inte acture | egory -<br>egrated | Number of Staff | Manufa Engineering N Manufacturing Facilities Engi Shift Manager Failure Analys Integration Er Automation E Factory Mana Yield Enginee | pational Category - acture of Integrated Circuits Manager g Manager ineering/Technician r sis Engineer ngineer/Technician ager er  % Projected to leave or retire | Number of Staff   |

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|-----------------------------------|---|---|--|--|--|---|----------------------------|
|                                   |   | CORPOR                                      | ATE LEVEL RES                                    | SPONSE                                 |  |   |                            |
| Section 11 For years 2 remain und | 2013-2016 provide your organization's U   | .S. and non-U.S. sa                         | les information. F                               | For 2017, project v                    | whether your sale                      | es will increase, de                          | ecrease or                 |
|                                   | F   | eporting Schedule:                          |  | Cale                                   | ndar Year/Fisca                        | l Year  |                            |
| Reco                              | rd \$ in Thousands, e.g. \$12,000.00 = surve  | ey input of \$12                            | 2013   | 2014                                   | 2015                                   | 2016  | 2017*                      |
| A.                                | Total Sales, all Customers (in \$)  |   |  |  |  |   |                            |
| B.                                | Total IC-Related Sales, all Customers U.S./   | Non-U.S. ( in \$)                           |  |  |  |   |                            |
| C.                                | Total U.S. IC-Related Sales - as a % of B   |   |  |  |  |   |                            |
| D.                                | Total Non-U.S. IC-Related Sales - as a % o  | f B   |  |  |  |   |                            |
| E.                                | Direct sales of Custom IC Products (including to U.S. Government customers (in \$)  | ng design services)                         |  |  |  |   |                            |
| F.                                | Is your organization dependent of U.S.  | Government sales f                          | or its ongoing via                               | bility?                                |  |   | Yes/No                     |
|                                   | Identify your organization's 1) top five of primary type of IC product supplied (IC product; and 3) indicate whether the product; | designs or fabricate<br>oducts were supplie | ed product) sold to<br>d under DMEA To           | them and the es                        | timated revenue tification.            |   |                            |
| G.                                | Commercial End Customer Name  | Country                                     | Estimated 2016<br>Revenue - All<br>Product Sales |  | oduct Type<br>n Revenue)               | Estimated 2016<br>Revenue<br>-Primary Product | DMEA<br>Trusted<br>Program |
|                                   |   |   |  | Drop-Down of 23 Pro                    | oduct Classes                          |   | Yes/No                     |
|                                   |   |   |  |  |  |   |                            |
|                                   | Identify your organization's 1) top five L 2) state the primary type of IC product s the primary product; and 3) indicate wh      | supplied (IC designs                        | or fabricated provere supplied und               | duct) sold to then<br>ler DMEA Trusted | n and the estima<br>I Access certifica | ted revenue for 20<br>ation.                  |                            |
|                                   | тор 3 о.з.  | Sovernment Custo                            |  | II FIOGUCES (NOII                      | -cora, by Nev                          |   | 51454                      |
| H.                                | Government End Customer Name  | Federal Agency                              | Estimated 2016 Revenue - All Product Sales       |  | duct Type<br>Revenue)                  | Estimated 2016 Revenue -Primary Product       | DMEA<br>Trusted<br>Program |
|                                   |   |   |  | Drop-Down of 23 Pro                    | oduct Classes                          |   | Yes/No                     |
|                                   |   |   |  |  |  |   |                            |
|                                   |   |   |  |  |  |   |                            |
|                                   | Comments:   |   | I  | <u> </u>                               |  | <u> </u>                                      | ı                          |
| exempt fro                        | e of financial information is required f<br>om Freedom of Information Act (FOIA<br>on's financial data.                           |   |  |  |  |   |                            |
|                                   | BUSINESS C  | ONFIDENTIAL - Pe                            | r Section 705(d)                                 | of the Defense F                       | Production Act                         |   |                            |

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# CORPORATE LEVEL RESPONSE

# **Section 12: Financials**

Provide the following Income Statement and Balance Sheet financial line items for your organization for years 2013-2016 below. Furnish full-year estimates for 2016.

|                                      | · ·                                |   |                                |      |      |  |  |  |  |
|--------------------------------------|------------------------------------|---|--------------------------------|------|------|--|--|--|--|
|                                      | Reporting Schedule:                | (Fiscal Year/Calendar Year)                                     |                                |      |      |  |  |  |  |
| Income Statement (Select Line Items) |                                    | Record \$ in Thousands, e.g. \$12,000.00 = survey input of \$12 |                                |      |      |  |  |  |  |
| ШК                                   | come Statement (Select Line Items) | 2013  | 2014                           | 2015 | 2016 |  |  |  |  |
| A.                                   | Net Sales (and other revenue)      |   |                                |      |      |  |  |  |  |
| B.                                   | Cost of Goods Sold                 |   |                                |      |      |  |  |  |  |
| C.                                   | Total Operating Income (Loss)      |   |                                |      |      |  |  |  |  |
| D.                                   | Earnings Before Interest and Taxes |   |                                |      |      |  |  |  |  |
| E.                                   | Net Income                         |   |                                |      |      |  |  |  |  |
|                                      | Source of Balance Sheet Items:     |   | (Corporate/Whole Organization) |      |      |  |  |  |  |
|                                      | Reporting Schedule:                | (Fiscal Year/Calendar Year)                                     |                                |      |      |  |  |  |  |
|                                      | Balance Sheet (Select Line Items)  | Record \$ in Thousands, e.g. \$12,000.00 = survey input of \$12 |                                |      |      |  |  |  |  |
|                                      | Balance Sheet (Select Line Items)  | 2013  | 2014                           | 2015 | 2016 |  |  |  |  |
| A.                                   | Cash                               |   |                                |      |      |  |  |  |  |
| B.                                   | Inventories                        |   |                                |      |      |  |  |  |  |
| C.                                   | Current Assets                     |   |                                |      |      |  |  |  |  |
| D.                                   | D. Total Assets                    |   |                                |      |      |  |  |  |  |
| E.                                   | Current Liabilities                |   |                                |      |      |  |  |  |  |
| F.                                   | Total Liabilities                  |   |                                |      |      |  |  |  |  |
|                                      | Comments:                          |   |                                |      |      |  |  |  |  |

Disclosure of financial information is required for both public and private companies. All financial data is treated as Business Proprietary and exempt from Freedom of Information Act (FOIA) requests. Providing BIS with financial information will not result in the public release of you organization's financial data.

BUSINESS CONFIDENTIAL - Per Section 705(d) of the Defense Production Act

|      | Reporting of Significant One-Time Events   |  |  |  |  |  |  |
|------|--|--|--|--|--|--|--|
| Year | Instruction: Provide an explanation of any significant one-time events that would skew assessments of the economic performance of your organization. |  |  |  |  |  |  |
| 2013 |  |  |  |  |  |  |  |
| 2014 |  |  |  |  |  |  |  |
| 2015 |  |  |  |  |  |  |  |
| 2016 |  |  |  |  |  |  |  |

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| Section 1 | l3: Acquisi   | tions, Divestitures, Mergers and Jo  |  | ATE LEVEL RESP             | ONSE                  |                              |                                    |  |  |  |  |  |
|           |   | Acquisitions, Divestitures, and Mergers  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           | How many  | Integrated Circuit-related acquisitions, dive  | estitures and mergers has your organiz   | zation been party to s     | ince 2013?            | If none, a "0" must be       | placed in the box.                 |  |  |  |  |  |
|           | Identify you description  | Identify your organization's five most recent Integrated Circuit-related acquisitions, divestitures and mergers, going back no more than five years. Identify the primary objective of each event listed and provide a |  |                            |                       |                              |                                    |  |  |  |  |  |
|           |   | Organization Name  | Type of Activity   | Country                    | Year                  | Primary Objective            | Explain (optional                  |  |  |  |  |  |
| A.        | 1   |  | Acquisition  |                            |                       |                              |                                    |  |  |  |  |  |
|           | 2   |  | Divestiture  |                            |                       |                              |                                    |  |  |  |  |  |
|           | 3   |  | Merger   |                            |                       |                              |                                    |  |  |  |  |  |
|           | 4   |  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           | 5   |  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           |   |  |  | Joint Ventur               | es                    |                              |                                    |  |  |  |  |  |
|           | How many Integrated Circuit-related joint ventures does your organization currently participate in? |  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           | Identify you  | Identify your organization's current Integrated Circuit-related joint venture relationships, including public/private R&D partnerships. Select the primary objective of the joint venture and provide a description.   |  |                            |                       |                              |                                    |  |  |  |  |  |
|           |   | Organization Nam   | ne   | Country                    | Year                  | Primary Objective            | Explain (optional                  |  |  |  |  |  |
| В.        | 1   |  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           | 2   |  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           | 3   |  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           | 4   |  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           | 5   |  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           |   | Have any non-U.S. governments (includi<br>percent or more of stockholder voting sha  |  | lirectly or indirectly, in | your organization - a | nd collectively control five | Yes - Directly/Yes - Indirectly/No |  |  |  |  |  |
| C.        | 1   | If you answered "yes" explain in the space   | nswered "yes" explain in the space below the nature of the investment and identify the non-U.S. government(s). |                            |                       |                              |                                    |  |  |  |  |  |
|           |   |  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           | Co  | mments:  |  |                            |                       |                              |                                    |  |  |  |  |  |
|           |   |  | BUSINESS CONFIDENTIAL - Pe   | r Section 705(d) o         | f the Defense Proc    | luction Act                  |                                    |  |  |  |  |  |
|           |   |  | DOS.ITEGG GOIN IDENTIAL - FE   | . 00011011 /00(u) 0        | THE Deletibe FIOL     | aution Aut                   |                                    |  |  |  |  |  |

| Primary Objective Dropdown      |                           |  |  |  |  |
|---------------------------------|---------------------------|--|--|--|--|
| Access to government contracts  | Market Access             |  |  |  |  |
| Access to intellectual property | R&D access/coordination   |  |  |  |  |
| Bankruptcy restructuring        | Reduce costs              |  |  |  |  |
| Broaden customer base           | Regulatory                |  |  |  |  |
| Develop new capabilities        | Tax-related               |  |  |  |  |
| Expand Product Lines            | Vertical integration      |  |  |  |  |
|                                 | Other objective (Explain) |  |  |  |  |

| < Primary Objective Dropdown |                      |  |  |  |  |
|------------------------------|----------------------|--|--|--|--|
| Cost Reduction               | Market Access        |  |  |  |  |
| Access to technology         | Product Improvements |  |  |  |  |
| Other                        | Risk sharing         |  |  |  |  |

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|---------------|--|--|-----------------------------|---------------------|-----------------|---------------|-------------------|---------------|-------------------|------|-----------|
| Section 14: 0 | Capital E  | xpenditures                                      |                             |                     |                 |               |                   |               |                   |      |           |
|               |  |  | CORPORA                     | TE LEVEL            | RESPONSE        |               |                   |               |                   |      |           |
|               | id your or<br>016?   | ganization track capital expenditure financials  | between 2013 and            |                     |                 |               | If not, enter "0  | )" in section | В                 |      |           |
| •             |  | Capital Expenditure Reporting Schedule:          |                             |                     |                 |               | Calendar Yea      | r/Fiscal Yea  | ar                |      |           |
|               |  | Capital Expenditure Category                     |                             |                     | Red             | cord \$ in Th | ousands, e.g. \$1 | 2,000.00 = s  | urvey input of \$ | 12   |           |
|               |  | Capital Experiordine Category                    |                             | 2                   | 2013            | 2             | 2014              | 2             | 2015              | 2    | 016       |
|               |  |  |                             | U.S.                | Non-U.S.        | U.S.          | Non-U.S.          | U.S.          | Non-U.S.          | U.S. | Non-U.S.  |
|               | 1  | Total Capital Expenditures                       |                             |                     |                 |               |                   |               |                   |      |           |
| В. —          | 2  | Total Integrated Circuit-related Capital Expen   |                             |                     |                 |               |                   |               |                   |      |           |
| Б.            |  | Machinery and Equipment [as a % of row 1]        |                             |                     |                 |               |                   |               |                   |      |           |
|               | 4  | IT, Computers, Software [as a % of row 1]        |                             |                     |                 |               |                   |               |                   |      |           |
|               |  | Land, Buildings, and Leasehold Improvement       | s [as a % of row 1]         |                     |                 |               |                   |               |                   |      |           |
|               |  | Other [Write In]                                 |                             |                     |                 |               |                   |               |                   |      |           |
| Lir           | ines 1 thro  | ough 4 must total 100%                           |                             | 0%                  |                 | 0%            |                   | 0%            |                   |      | 0%        |
| Fr            | From 2013-2016, what was the most significant factor in dictating your organ |  | dictating your organization | n's Capital E       | xpenditures?    |               |                   |               |                   |      |           |
| C. 11         |  | Explain:   |                             | -                   | •               |               |                   |               |                   |      |           |
| D             | ank vaur   | organization's tan 2 conital avacaditure priorit | on for 2012 2016, ontinin   | atad prioritia      | o for 2017 2021 | L and near    | do o briof docor  | intion        |                   |      |           |
| Ra            | ank your   | organization's top 3 capital expenditure priorit | es for 2013-2016, anticipa  | ated prioritie      | S 101 2017-2021 | i, and provi  | de a briei descr  | iption.       |                   |      |           |
|               | Priority   |  | 2013                        | 2013-2016           |                 | 2017-2021     |                   | Description   |                   |      |           |
|               | 1  | Replace old machinery and equipment              |                             | 1                   |                 | 1             |                   |               |                   |      |           |
| D.            | 2  | Improve productivity                             |                             | 2                   | 2               |               |                   |               |                   |      |           |
| D.            | 3  | Expand capacity                                  |                             | 3                   | 3               | i             |                   |               |                   |      |           |
|               | 4  | Add new capability                               |                             |                     |                 |               |                   |               |                   |      |           |
|               | 5  | Upgrade technology                               |                             |                     |                 |               |                   |               |                   |      |           |
|               | 6  | Meet specific customer requirements              |                             |                     |                 |               |                   |               |                   |      |           |
|               | 7  | Other [Write In]                                 |                             |                     |                 |               |                   |               |                   |      |           |
|               |  | Comments:  |                             |                     |                 |               |                   |               |                   |      |           |
|               |  | BUSINES  | S CONFIDENTIAL - Per        | Section 70          | (d) of the Defe | ense Produ    | ction Act         |               |                   |      |           |

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|------------|--------------|--|---|--------------------|-----------------------|---------------|--|--|
| Section 1  | 5: Resear    | ch & Development   |   |                    |                       |               |  |  |
|            |              | CORPORATE LEVEL  | RESPONSE  | 1                  |                       |               |  |  |
| A.         | Does you     | r organization perform Research and Development (R&D)?   |   | Yes/No             | If not, proceed to se | ection 16     |  |  |
| In Questio | on C, identi | d your organization's total R&D dollar expenditures for years 2013-<br>ify your organization's R&D funding sources, by percent of total R&I<br>unding sources reported (section C) can exceed total expenditures | O dollars sourced.  | for a given year.  |                       |               |  |  |
|            |              | Reporting Schedule:  |   | Ca                 | lendar Year/Fiscal Y  | ear           |  |  |
|            |              |  | Record \$ in  | Thousands, e.g. \$ | 12,000.00 = survey    | input of \$12 |  |  |
|            |              |  | 2013  | 2014               | 2015                  | 2016          |  |  |
|            | 1            | Total R&D Expenditures   | \$  |                    |                       |               |  |  |
| B.         | 2            | Basic Research (as a percent of B1)  | %   |                    |                       |               |  |  |
|            | 3            | Applied Research (as a percent of B1)  | %   |                    |                       |               |  |  |
|            | 4            | Product/Process Development (as a percent of B1)   | %   |                    |                       |               |  |  |
|            | 5            | Total of 2 - 4 (must equal 100%)   | 0%  | 0%                 | 0%                    | 0%            |  |  |
|            |              |  | Record \$ in Thousands, e.g. \$12,000.00 = survey input of \$12 |                    |                       |               |  |  |
|            |              |  | 2013  | 2014               | 2015                  | 2016          |  |  |
|            | 1            | Total R&D Funding Sources  | \$  |                    |                       |               |  |  |
|            | 2            | Parent Company (Internal)  | %   |                    |                       |               |  |  |
| C.         | 3            | Total Federal Government   | %   |                    |                       |               |  |  |
|            | 4            | State and Local Government   | %   |                    |                       |               |  |  |
|            | 5            | U.S. Private Entity [includes industry, universities]  | %   |                    |                       |               |  |  |
|            | 6            | Foreign Investors [includes industry, governments]   | %   |                    |                       |               |  |  |
|            | 8            | Other (specify here)   | %   |                    |                       |               |  |  |
|            | 9            | Total of 2 - 8 (must equal 100%)   | 0%  | 0%                 | 0%                    | 0%            |  |  |
|            |              | t the percentages of your organization's total annual R&D expenditi<br>erformed in U.S. and Non-U.S. locations for 2013-2016   | 0   |                    | Ü                     | anufacturing  |  |  |
| D.         |              | R&D Expenditures For Integrated<br>(Corporate or Integrate   |   |                    |                       |               |  |  |
| Б.         | Total Into   | grated Circuit-Related R&D Expenditures  | 2013  | 2014               | 2015                  | 2016          |  |  |
|            | Total litte  | Percent Performed at All U.S. Locations  | <u>2013</u><br>%  | 2014               | 2010                  | 2010          |  |  |
|            |              | Percent Performed at All Non-U.S. Locations  | %<br>%  |                    |                       |               |  |  |
|            |              | Total Integrated Circuit R&D Expenditures  |   |                    |                       |               |  |  |
|            |              |  | Ψ   | <u> </u>           | <u> </u>              | <u> </u>      |  |  |
|            |              | Comments:  |   |                    |                       |               |  |  |
|            |              | BUSINESS CONFIDENTIAL - Per Section 70   | 5(d) of the Defens  | e Production Act   |                       |               |  |  |

Data Confirmation

Total 2016 R&D

Expenditures

None

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|------------|---|-----------------------------------|--|------------------------------|--|--------------------------------------|----------------------|-------------------------------|-----------------------------------|----------------------|--|--|
| Section 16 | 6a - Export Re                              | gulation &                        | Trade Issues: Regulat  |                              | PORATE LEVEL   | DESPONSE                             |                      |                               |                                   |                      |  |  |
|            |   |                                   |  | COM                          | 'UKATE LEVEL   |                                      |                      | Yes/No                        |                                   |                      |  |  |
| A.         | Identif                                     | v the Integra                     | ted Circuit-related products                                       | s that your organization     | IC Designs  exports:    Designs   De |                                      |                      | Yes/No                        |                                   |                      |  |  |
|            |   |                                   |  |                              |  | Partially Built ICs Complete IC Prod |                      | Yes/No                        |                                   |                      |  |  |
|            |   |                                   | ort control system (Export A                                       |                              |  | rce Control List [CC                 | CL]), or             | EAR/CCL                       | Yes/                              | /No                  |  |  |
| B.         |   |                                   | s Regulations [ITAR]/U.S. M<br>gn services and manufactu           |                              | for the export or in   | itegrated Circuit-reid               | ated products        | ITAR/USML                     | /No                               |                      |  |  |
|            | If you do not uti                           |                                   | port control licenses for Inte                                     | grated Circuit -related      | products or service  | es, select "No" in th                | ne box and           | 1174400                       | Yes/No                            | 110                  |  |  |
|            |   |                                   | export sales opportunities of                                      |                              |  |                                      |                      | Lost Sales?*                  | Lost Export Sa                    | ales Estimate        |  |  |
| C.         |   |                                   | titors because of U.S. expo<br>ar amount of lost export sal        |                              |  |                                      | /CCL                 | Yes/No                        | \$                                |                      |  |  |
|            | *Loct Cales: Are                            | attributed to bi                  | indian written supply contract                                     | to (not optimates) of a etc  | ated dollar value that   |                                      | USML                 | Yes/No                        | rmined that the Integr            |                      |  |  |
|            |   |                                   | inding, written supply contracts<br>and or manufactured devices)   |                              |  |                                      | because a review or  | export regulations deter      | mined that the integra            | ated Circuit-related |  |  |
|            | State whether Lat right.                    | J.S. export co                    | ontrol regulations since 201                                       | 13 directly affected you     | ur organization's Int  | tegrated Circuit bus                 | siness in any of the | e ways listed below.          | If "Yes," explain in t            | he box provided      |  |  |
|            |   |                                   | Impact   |                              | Resp   | oonse                                |                      | Explai                        | nation                            |                      |  |  |
|            | 1   |                                   | r organization's Integrated (<br>nd development program            | Circuit-related              | Y  | ′/N                                  |                      |                               |                                   |                      |  |  |
|            |   |                                   |  |                              |  | Z/CCL                                |                      |                               |                                   |                      |  |  |
|            | 2   |                                   | e export of products or servi<br>L or ITAR/USML related co         |                              |  | /USML<br>oth                         | _                    |                               |                                   |                      |  |  |
|            |   |                                   |  |                              | N/A  |                                      |                      |                               |                                   |                      |  |  |
|            |   |                                   |  |                              | EAR/CCL  |                                      |                      |                               |                                   |                      |  |  |
| D.         |   |                                   | composition of specific Inte                                       | ITAR/USML                    |  |                                      |                      |                               |                                   |                      |  |  |
|            |   | related busin                     | ness lines   |                              | oth<br>I/A   |                                      |                      |                               |                                   |                      |  |  |
|            |   |                                   |  | EAR/CCL                      |  |                                      |                      |                               |                                   |                      |  |  |
|            |   |                                   | relocated Integrated Circuit                                       | t-related facilities         | ITAR/  | ITAR/USML                            |                      |                               |                                   |                      |  |  |
|            |   |                                   | United States due to regula  | atory burdens.               |  | Both                                 |                      |                               |                                   |                      |  |  |
|            |   |                                   |  |                              | N N  | I/A                                  |                      |                               |                                   |                      |  |  |
|            | 5   | Integrated C                      | rganization's avoided buying<br>Circuit-related products or s      | services.                    | Y/N  |                                      |                      |                               |                                   |                      |  |  |
|            | 6   |                                   | n-U.S. organizations to offe<br>CL-free" Integrated Circuit-re     |                              | Y/N  |                                      |                      |                               |                                   |                      |  |  |
| E.         | State whether r                             | eforms in exp                     | port control regulations (EA                                       | AR/CCL and ITAR/USI          | ML) have affected y  | your Integrated Circ                 | cuit business:       |                               |                                   | Yes/No               |  |  |
|            |   | dicating from                     | ted below, identify how refo<br>the list provided how expo<br>ume. |                              |  |                                      |                      |                               |                                   |                      |  |  |
|            |   | Impacts of Export Control Reforms |  |                              |  |                                      |                      |                               |                                   |                      |  |  |
|            | Techno                                      | ology                             |  | Regul                        | latory Impacts   |                                      |                      | Range of Trading<br>Companies | Number of<br>Trading<br>Countries | Business<br>Volume   |  |  |
| F.         |   | .03)                              | Impact #1  | Impac                        | :t #2  | Impa                                 | act #3               |                               |                                   |                      |  |  |
|            | Microwave Monolithic<br>Integrated Circuits |                                   | Reduced Paperwork  | Wider business opportunities | Other #1   |                                      |                      | Increase                      | Increase                          | Increase             |  |  |
|            |   |                                   | Increased Paperwork  | Fewer business opportunities |  | <del></del>                          |                      | Decrease                      | Decrease                          | Decrease             |  |  |
|            | Transmit/Receiv                             | vo Modulos                        | Reduced Licensing Time   | Removed some controls        | Other # 2  |                                      |                      | No Change                     | No Change                         | No Change            |  |  |
|            | Transmittecen                               | ve iviodules                      | Increased Licensing Time   | Added some controls          |  |                                      |                      | Other                         |                                   |                      |  |  |
|            | Comments:                                   |                                   |  |                              |  |                                      |                      |                               |                                   |                      |  |  |
|            |   |                                   | BUSINES  | S CONFIDENTIAL -             | Per Section 70   | 5(d) of the Defer                    | se Production        | Act                           |                                   |                      |  |  |

Previous Page Table of Contents Next Page Section 17a - Trade and Intellectual Property Issues From the list below, identify the methods your organization uses to transfer Integrated Circuit-related design and manufacturing intellectual property on a legal, authorized basis to U.S. and non-U.S. destinations. Non-U.S. Design IP or Manufacturing IP Methods US Location(s) Location(s) Licensing Intellectual Property Yes/No Yes/No Design IP Joint Ventures Manufacturing IP Research collaborations 3oth Α Participation in scientific/technical conferences Information provided to potential investors **Debt Financing** Non-Disclosure Agreements Other [Write in] 8 From the list below, identify the methods by which unauthorized transfers of your company's Integrated Circuit-related design and manufacturing intellectual property have occurred. If yes, identify the types of IP. Non-U.S. US Location(s) Methods Design IP or Manufacturing IP Location(s) Cyber security intrusions Yes/No Yes/No Design IP Planting staff in your company Manufacturing IP Physical break-ins at company facilities 3 Both Business partners **Dumpster Diving** 6 Former employees В **Employees** External IT System Contractors 8 9 Persons performing R&D with your company Company campus Wi-Fi Network Interceptions 10 11 Persons speaking to outside industry analysts/experts 12 Persons speaking with your bankers/financiers 13 Persons speaking with contractors and suppliers 14 Violation of Non-Disclosure Agreements 15 Other [Write in] Type of IP In the years 2013-2016, did your organization experience unauthorized transfers of Integrated Circuit-1 related design and/or manufacturing Intellectual Property? Design/Manufacturing/Both/Neither Design IP Manufacturing IP If "Yes," report the number of instances this occured for Design IP and Manufacturing IP? 2 Yes/No Country Country Does your company know the country location(s) of the most frequent perpetrators of the unauthorized transfers of your company's Integrated Circuit-related intellectual property? If 3 "Yes" identify the countries. Yes/No/Not Yes/No/Not CCL/EAR Was the intellectual property subject to any the following export control applicable applicable С 4 regulations: USML/ITAR U.S. Department of Defense Yes/No U.S. Department of Commerce U.S. Department of State 5 Did your organization report the incident(s) to the: Federal Bureau of Investigation State/Local police authorities U.S. Department of Energy Other [Write In] In the past five years has your organization experienced a loss of access to critical Integrated Circuit-Yes/No/Not applicable related Intellectual Property? Comments: BUSINESS CONFIDENTIAL - Per Section 705(d) of the Defense Production Act

OMB 0694-0119 ROCIS Submission Return to Table of Contents Next Pac revious Page Section 17b: Trade and Intellectual Property Issues CORPORATE LEVEL RESPONSE Identify all trade practices and requirements that your organization has encountered at any time since 2013 in countries where it currently conducts business or seeks to do business directly or indirectly through third parties. Then, identify up to three countries where these practices or requirements have been encountered and whether they persist to date. **Trade Practices** Persists Today? Country #2 Persists Today? Persists Today? Yes/No Country #1 Country #3 Yes Yes Yes Tariffs on the Integrated Circuit-related products and services that your organization sells National trade policy to phase out the use of Integrated Circuit-related products designed or Nο No Nο made outside of their country Threats to boycott your organization's products unless your organization allows substantial N/A N/A investment by entities from that country Manipulation of your organization's publicly traded stock as a consequence of refusing to transfer intellectual property or establish design and/or manufacturing operations in that country Denied timely access to the country's market Comments: Persists Today? Country #2 Persists Today? Country #3 Persists Today? **Conditional Trade Requirements** Yes/No Country #1 Yes Transfer of Integrated Circuit-related device intellectual property (trade secrets, patents, etc.) Yes Yes Transfer of Integrated Circuit-related manufacturing process intellectual property (trade secrets, No No No patents, etc.) N/A N/A Outsource design of Integrated Circuit-related products to their country Establish Integrated Circuit-related design operations in their country Outsource the manufacture of Integrated Circuit-related products to their country Establish Integrated Circuit-related manufacturing operations in their country

BUSINESS CONFIDENTIAL - Per Section 705(d) of the Defense Production Act

Required investment/equity from non-US companies in order to maintain market access Mandatory joint ventures as means to achieve transfers on design and/or manufacturing

Comments:

intellectual property and know-how

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|--------|--|---------------|------------------------|---------------------------|-----------------------------|
| ction  | 18: Competitiveness                        |               | CORPORATE LEVE         | I PESPONSE                |                             |
|        |  |               |                        |                           |                             |
|        | Rank your organization's top five issues   | affecting the | long-term competitiver | ness of your organization | and provide an explanation. |
|        | Issue                                      |               | 2013-2016              | 2017-2021                 | Explanation (optional):     |
|        | Aging equipment, facilities, or infrastruc | ture          | 1                      | 1                         |                             |
|        | Aging workforce                            |               | 2                      | 2                         |                             |
|        | Competition - domestic                     |               | 3                      | 3                         |                             |
|        | Competition - foreign                      |               | 4                      | 4                         |                             |
|        | Counterfeit parts                          |               | 5                      | 5                         |                             |
|        | Cybersecurity                              |               |                        |                           |                             |
|        | Environmental regulations/remediation      |               |                        |                           |                             |
|        | Environmental regulations/remediation      | non-U.S.      |                        |                           |                             |
|        | Export controls; ITAR/USML; EAR/CCL        |               |                        |                           |                             |
|        | Forced localization                        |               |                        |                           |                             |
|        | Government acquisition processes           |               |                        |                           |                             |
|        | Government purchasing volatility           |               |                        |                           |                             |
|        | Government regulatory burden               |               |                        |                           |                             |
|        | Healthcare costs                           |               |                        |                           |                             |
| A.     | Health and safety regulations              |               |                        |                           |                             |
|        | Imports                                    |               |                        |                           |                             |
|        | Industrial Espionage                       |               |                        |                           |                             |
|        | Intellectual property/patent infringement  | t             |                        |                           |                             |
|        | Labor availability/costs                   |               |                        |                           |                             |
|        | Material input availability                |               |                        |                           |                             |
|        | Product obsolescence                       |               |                        |                           |                             |
|        | Pension costs                              |               |                        |                           |                             |
|        | Proximity to customers                     |               |                        |                           |                             |
|        | Proximity to suppliers                     |               |                        |                           |                             |
|        | R&D costs                                  |               |                        |                           |                             |
|        | Reduction in commercial demand             |               |                        |                           |                             |
|        | Reduction in USG demand                    |               |                        |                           |                             |
|        | Taxes                                      |               |                        |                           |                             |
|        | Worker/skills retention                    |               |                        |                           |                             |
|        | Other (specify)                            |               |                        |                           |                             |
|        | Other                                      | (specify)     |                        |                           |                             |
|        | Comments:                                  |               |                        |                           |                             |
|        | DIIGINE                                    | SS CONFIDE    | MTIAL - Dor Soction 7  | 05(d) of the Defense Pro  | oduction Act                |

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|---------|--------|---|-----------------------|--|---|-----------------------------------|---|-----------------------------------|-------------------------------------|---------------------------------|
| Section | 19: Cy | ber Security  |                       |  |   |                                   |   |                                   |                                     |                                 |
|         |        | Estimate your organization's spending on ph   | ysical and cyber se   | ecurity, in thousands                          | of dollars, and sta                                 | te the number of se               | curity incidents you                    | r organization has r              | ecorded in each yea                 | ar.                             |
|         |        | Reporting Schedule:   | December 10 There     |  | 0.00  |                                   |   |                                   |                                     |                                 |
|         |        |   | 0.00 = survey inpu    | 014  | 2   | 015                               | 1 20                                    | 16*                               |                                     |                                 |
| A.      |        |   | Incidents             | 013<br>Expenditures                            | Incidents   | Expenditures                      | Incidents                               | Expenditures                      | Incidents                           | Expenditures                    |
|         |        | 1 Cyber Security  | #                     | \$   | #   | \$                                | #                                       | \$                                | #                                   | \$                              |
|         |        | 2 Physical Security   | #                     | \$   | #   | \$                                | #                                       | \$                                | #                                   | \$                              |
|         |        | * Furnish full year estimates for 2016 if data  |                       |  | (55150)   |                                   |   | (=1.15                            |                                     |                                 |
|         |        | Is your organization aware of Defense Fede Reported Cyber Incident Information?   | ral Acquisition Regi  | ulation Supplement                             | (DFARS) 252.204-                                    | 7009, Limitations on              | the Use or Disclos                      | sure of Third-Party C             | Contractor                          | Yes/No                          |
| _       | 1      | http://www.acq.osd.mil/dpap/dars/dfars/h  | tml/current/25220     | 4.htm  |   |                                   |   |                                   |                                     | 163/140                         |
| B.      |        | Explain:  |                       |  |   |                                   |   |                                   |                                     |                                 |
|         | 2      | Who is responsible for administering your or  |                       |  |   |                                   |   |                                   |                                     | Dropdown                        |
|         | 3      | Who is responsible for administering your or<br>is the computer or computer network that ho                                     |                       |  |   | tion (CSI) connected              | to the Internet, eit                    | her directly or via an            | n intermediary                      | Dropdown                        |
|         |        | network or server?  |                       |  |   | (,                                | , |                                   |                                     |                                 |
|         | 1      |   |                       |  |   |                                   |   |                                   |                                     | Yes/No                          |
|         |        | *This includes customer/client information, fi  |                       |  |   |                                   |   |                                   |                                     |                                 |
|         |        | manufacturing and production line information<br>chain information.   | ni, paterit and trade | mark imormation, i                             | esearch and deven                                   | opment information,               | regulatory/complia                      | nice iniornation, and             | a supplier/supply                   |                                 |
|         |        |   | 2.2                   |  |   |                                   |   |                                   | External Cloud Service              | Restrict/Prohibit/No/U          |
|         |        | Does your organization either restrict or prof<br>Information (CSI) outside of the U.S.?  | nibit your external c | ioud service or exte                           | rnai data storage p                                 | provider(s) from stori            | ng Commercially S                       | ensitive                          | Providers  External Data Storage    | known<br>Restrict/Prohibit/No/L |
|         | 2      | miorination (edi) dubide of the e.e.:   |                       |  |   |                                   |   |                                   | Providers                           | known                           |
|         | 2      |   |                       |  |   |                                   |   |                                   | External Cloud Service<br>Providers | (% Entry Only)                  |
|         |        | Estimate the percentage of your organization  | n's Commercially S    | ensitive Information                           | (CSI) that is stored                                | d with:                           |   |                                   | External Data Storage               |                                 |
|         |        |   |                       |  |   |                                   |   |                                   | Providers                           | (% Entry Only)                  |
|         |        |   |                       | Advanced                                       |   |                                   |   | Identity and access               |                                     |                                 |
|         |        |   |                       | authentication<br>(biometrics, tokens          | <yes no=""></yes>                                   | End-point protection              | <yes no=""></yes>                       | Identity and access<br>management | <yes no=""></yes>                   |                                 |
|         |        | Does your organization use the following clo  | oud-based security    | etc.)  |   |                                   |   |                                   |                                     |                                 |
|         | 3      | protocols?  |                       | Real-time                                      |   |                                   |   |                                   |                                     |                                 |
|         |        |   |                       | monitoring/analytics                           | <yes no=""></yes>                                   | Threat intelligence               | <yes no=""></yes>                       | Other (specify)                   | <yes no=""></yes>                   |                                 |
|         |        |   |                       |  |   |                                   |   |                                   |                                     |                                 |
|         |        | Explain:  |                       |  |   |                                   |   |                                   |                                     |                                 |
| C.      |        | Does your organization have structured met  |                       | the following                                  | <yes explain<="" no="" not="" td=""><td></td></yes> |                                   |   |                                   |                                     |                                 |
| О.      |        | types of Commercially Sensitive Information   | (see delimitions)?    |  | Applicable>   |                                   |   |                                   |                                     |                                 |
|         |        | Customer/client information   |                       |  |   |                                   |   |                                   |                                     |                                 |
|         |        | Financial information and records   |                       |  |   |                                   |   |                                   |                                     |                                 |
|         |        | Human resources information/employee date   | a                     |  |   |                                   |   |                                   |                                     |                                 |
|         |        | Information subject to export control regulati  |                       | AR)  |   |                                   |   |                                   |                                     |                                 |
|         |        |   |                       | <u>,                                      </u> |   |                                   |   |                                   |                                     |                                 |
|         |        | Intellectual property related information   |                       |  |   |                                   |   |                                   |                                     |                                 |
|         | 4      | Internal communications including negotiatic<br>plans, and/or corporate strategy  | on points, merger ai  | nd acquisition                                 |   |                                   |   |                                   |                                     |                                 |
|         |        | Manufacturing and production line information   | on                    |  |   |                                   |   |                                   |                                     |                                 |
|         |        | Patent and trademark information  |                       |  |   |                                   |   |                                   |                                     |                                 |
|         |        | Regulatory/compliance Information   |                       |  |   |                                   |   |                                   |                                     |                                 |
|         |        | Research and development (R&D) related in   | formation             |  |   |                                   |   |                                   |                                     |                                 |
|         |        | Supply chain and sourcing information   |                       |  |   |                                   |   |                                   |                                     |                                 |
|         |        | -   |                       |  |   |                                   |   |                                   |                                     |                                 |
|         |        | Other (specify)   | L                     |  |   | <u> </u>                          |   |                                   |                                     |                                 |
|         |        | Using the drop-down lists and free-text entrice  Event  |                       | ne type(s) and seve                            |   | curity events that ha<br>ct Level | ve occurred at this<br>Frequency        |                                   | 013-2016.<br>in (incident and follo | w-up)                           |
|         | 1      | (Choose from Drop-Down)   |                       |  |   | vere                              | #                                       | Write in                          | in (incident and lone               | w-up)                           |
| D.      | 2      |   |                       |  |   |                                   |   |                                   |                                     |                                 |
|         | 3      |   |                       |  |   |                                   |   |                                   |                                     |                                 |
|         | 4      | 4 Other Cybersecurity Event (Specify) None  |                       |  |   |                                   |   |                                   |                                     |                                 |
|         | 5      | Other Cybersecurity Event   | (Spe                  | ecify)   |   |                                   |   |                                   |                                     |                                 |
|         |        | encourages recipients to report information of<br>i.gov/contact-us/field. CyWatch can be contact<br>activity, number of people, | cted by phone at 85   | 5-292-3937 or e-ma                             | ail at CyWatch@ic                                   | :.fbi.gov. When avail             | able, each report s                     | ubmitted should inc               | lude the date, time,                |                                 |
| Comn    | nents: |   |                       |  | ,,  |                                   |   |                                   |                                     |                                 |
|         |        | l   |                       |  |   |                                   | 34                                      |                                   |                                     |                                 |
|         |        |   | BUSINESS C            | ONFIDENTIAL - Pe                               | er Section 705(d) o                                 | of the Defense Prod               | duction Act                             |                                   |                                     |                                 |

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| Section 20: Certification  |  |  |  |  |  |
|  | response to this questionnaire is complete and correct to the best of his/her knowledge. It is a criminal offense to willfully make y of the United States Government as to any matter within its jurisdiction (18 U.S.C.A. 1001 (1984 & SUPP. 1197)). |  |  |  |  |
| Once this survey is complete, submit it via e-mail to: XXX@bis.c         | doc.gov. Be sure to retain a copy for your records and to facilitate any necessary edits or clarifications.  |  |  |  |  |
| Organization Name  |  |  |  |  |  |
| Organization's Internet Address  |  |  |  |  |  |
| Name of Authorizing Official   |  |  |  |  |  |
| Title of Authorizing Official  |  |  |  |  |  |
| E-mail Address   |  |  |  |  |  |
| Phone Number and Extension   |  |  |  |  |  |
| Date Certified   |  |  |  |  |  |
| In the box below, provide any additional comments or any other           | information you wish to include regarding this survey assessment.  |  |  |  |  |
|  |  |  |  |  |  |
| How many hours did it take to complete this survey?                      |  |  |  |  |  |
| BUSINESS CONFIDENTIAL - Per Section 705(d) of the Defense Production Act |  |  |  |  |  |